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4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision A (May 2020) to Revision B (February 2022)	Page
• 旧式の用語を使っている場合、すべてコマンドおよびレスポンスに変更。.....	1
• Changed <i>nRST is only dependent..</i> statement to: <i>nRST is dependent</i> in the nRST (Reset Output) section...	22

Changes from Revision * (November 2019) to Revision A (May 2020)	Page
• 「特長」のリストに「SLLA495 を参照」を追加.....	1
• 「特長」に「機能安全対応」を追加.....	1
• Added : See errata TLIN1028S-Q1 Duty Cycle Over V_{SUP}	7

5 概要 (続き)

スリープ・モードから LIN バスやピンによるウェイクアップが可能なため、非常に低い消費電流を実現できます。LIN バスには、ドミナント状態 (グラウンドに近い電圧) とリセッシブ状態 (バッテリーに近い電圧) という 2 つの状態があります。リセッシブ状態では、内蔵プルアップ抵抗 (45k Ω) および直列ダイオードにより、LIN バスが HIGH になります。レスポнда用途では、外付けプルアップ部品は不要です。コントローラ用途では、LIN 仕様に従って外付けプルアップ抵抗 (1k Ω) と直列ダイオードが必要です。

6 Pin Configuration and Functions

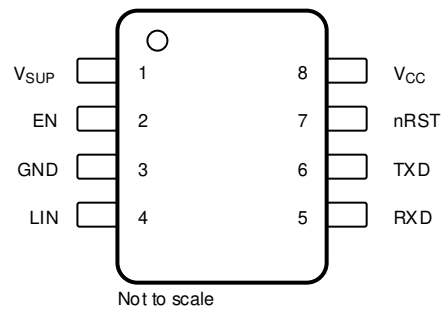


图 6-1. D Package, 8-Pin (SOIC), Top View

表 6-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME		
1	V _{SUP}	HV Supply In	Device supply voltage (connected to battery in series with external reverse-blocking diode)
2	EN	D I	Enable input
3	GND	GND	Ground ⁽²⁾
4	LIN	HV I/O	LIN bus single-wire transmitter and receiver
5	RXD	D O	RXD output (open-drain) interface reporting state of LIN bus voltage
6	TXD	D I	TXD input interface to control state of LIN output
7	nRST	D O	Reset output (active low)
8	V _{CC}	Supply Out	Output voltage from integrated LDO

(1) HV - High Voltage, DI - Digital Input, DO - Digital Output, HV I/O - High Voltage Input/Output

(2) When the thermal pad is present, it must be soldered to ground plane.

7 Specification

7.1 ABSOLUTE MAXIMUM RATINGS

(1)

		MIN	MAX	UNIT
V _{SUP}	Supply voltage range	−0.3	42	V
V _{LIN}	LIN Bus input voltage	−58	58	V
V _{CC50}	Regulated 5 V Output Supply	−0.3	6	V
V _{CC33}	Regulated 3.3 V Output Supply	−0.3	4.5	V
V _{nRST}	Reset output voltage	−0.3	V _{CC} + 0.3	V
V _{LOGIC_INPUT}	Logic input voltage	−0.3	6	V
V _{LOGIC_OUTPUT}	Logic output voltage	−0.3	6	V
I _{VCC}	V _{CC} supply current ⁽²⁾		300	mA
I _O	Digital pin output current	−8	8	mA
I _{O(nRST)}	Reset output current	−5	5	mA
T _J	Junction temperature	−40	165	°C
T _{stg}	Storage temperature range	−65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Device will enter thermal shutdown prior to hitting this limit but if the limit is reached the device may sustain permanent damage.

7.2 ESD RATINGS

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM) classification level H2: V _{SUP} , LIN, and WAKE with respect to ground	±8000	V
		Human body model (HBM) classification level 3A: all other pins, per AEC Q100-002 ⁽¹⁾	±4000	
		Charged device model (CDM) classification level C5, per AEC Q100-011	±750	

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 ESD RATINGS, IEC SPECIFICATION

			VALUE	UNIT
V _(ESD)	Electrostatic discharge per IEC 62228-2 ⁽¹⁾ , LIN, V _{SUP} terminal to GND	Contact discharge	±15000	V
		Indirect	±15000	V
V _(ESD)	Powered electrostatic discharge per SAE J2962-1 ⁽²⁾	Contact discharge	±8000	V
		Air discharge	±25000	
Transient	ISO 7637-2 and IEC 62215-3 transients per IEC 62228-2 ⁽¹⁾	Pulse 1	−100	V
		Pulse 2a	75	
		Pulse 3a	−150	
		Pulse 3b	100	

- (1) IEC 62228-2 ESD testing performed at third party. Different system-level configurations may lead to different results. Test reports available upon request.
- (2) SAE J2962-1 Testing performed at 3rd party US3 approved EMC test facility, test report available upon request.

7.4 RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
V _{SUP}	Supply voltage	5.5		28	V

7.4 RECOMMENDED OPERATING CONDITIONS (continued)

		MIN	NOM	MAX	UNIT
V _{LIN}	LIN bus input voltage	0		28	V
V _{LOGIC5}	Logic pin voltage	0		5.25	V
V _{LOGIC33}	Logic pin voltage	0		3.465	V
I _{OH(DO)}	Digital terminal HIGH level output current	-2			mA
I _{OL(DO)}	Digital terminal LOW level output current			2	mA
C _(VSUP)	V _{SUP} supply capacitor	100			nF
C _(VCC)	V _{CC} supply capacitor	10			μF
ESR _{CO}	Output ESR requirements	0.001		2	Ω

7.5 THERMAL INFORMATION

THERMAL METRIC ⁽¹⁾		TLIN1028x	UNIT
		D	
		8 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	119.4	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	51.5	°C/W
R _{θJB}	Junction-to-board thermal resistance	64.9	°C/W
ψ _{JT}	Junction-to-top characterization parameter	9.6	°C/W
ψ _{JB}	Junction-to-board characterization parameter	63.7	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	n/a	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

7.6 POWER SUPPLY CHARACTERISTICS

parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY VOLTAGE AND CURRENT						
V _{SUP}	Operational supply voltage (ISO/DIS 17987 Param 10)	Device is operational beyond the LIN defined nominal supply voltage range. See § 8-1 and § 8-2	5.5		36	V
V _{SUP}	Nominal supply voltage (ISO/DIS 17987 Param 10):	Normal and Standby Modes: Ramp V _{SUP} while LIN signal is a 10 kHz square wave with 50 % duty cycle and swing between 5.5 V ≤ V _{LIN} ≤ 28 V. See § 8-1 and § 8-2	5.5		28	V
		Sleep Mode	5.5		28	V
UV _{SUPR}	Under voltage V _{SUP} threshold	Ramp Up		3.5	4.2	V
UV _{SUPF}	Under voltage V _{SUP} threshold	Ramp Down	1.8	2.1	2.5	V
U _{VHYS}	Delta hysteresis voltage for V _{SUP} under voltage threshold			1.5		V
I _{SUP}	Transceiver and LDO supply current	Transceiver normal mode dominant plus LDO output			80	mA
I _{SUPTRXDOM}	Supply current transceiver only	Normal Mode: EN = V _{CC} , bus dominant: total bus load where R _{LIN} ≥ 500 Ω and C _{LIN} ≤ 10 nF		1.2	5	mA
		Standby Mode: EN = 0 V, bus dominant: total bus load where R _{LIN} ≥ 500 Ω and C _{LIN} ≤ 10 nF		1	1.8	mA

7.6 POWER SUPPLY CHARACTERISTICS (continued)

parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{\text{SUPTRXREC}}$	Supply current transceiver only	Normal Mode: $\text{EN} = V_{\text{CC}}$, Bus recessive: $\text{LIN} = V_{\text{SUP}}$,		450	775	μA
		Standby Mode: $\text{EN} = 0\text{ V}$, $\text{LIN} = \text{recessive} = V_{\text{SUP}}$, I_{OZH} from processor $\leq 1\text{ }\mu\text{A}$		38	55	μA
		Added Standby Mode current through the RXD pull-up resistor with a value of 100 k Ω : $\text{EN} = 0\text{ V}$, $\text{LIN} = \text{recessive} = V_{\text{SUP}}$, $\text{RXD} = \text{GND}^{(1)}$			55	
$I_{\text{SUPTRXSLEP}}$	Sleep mode supply current transceiver only	$5.5\text{ V} < V_{\text{SUP}} \leq 28\text{ V}$, $\text{LIN} = V_{\text{SUP}}$, $\text{EN} = 0\text{ V}$, TXD and RXD floating		17	33	μA
REGULATED OUTPUT V_{CC}						
V_{CC}	Regulated output	$V_{\text{SUP}} = 5.5\text{ to }28\text{ V}$, $I_{\text{CC}} = 1\text{ to }70\text{ mA}$	-2		2	%
$\Delta V_{\text{CC}}(\Delta V_{\text{SUP}})$	Line regulation	$V_{\text{SUP}} = 5.5\text{ to }28\text{ V}$, ΔV_{CC} , $I_{\text{CC}} = 10\text{ mA}$			50	mV
$\Delta V_{\text{CC}}(\Delta V_{\text{SUP}})$	Load regulation	$I_{\text{CC}} = 1\text{ to }70\text{ mA}$, $V_{\text{SUP}} = 14\text{ V}$, ΔV_{CC}			50	mV
V_{DROP}	Dropout voltage (5 V LDO)	$V_{\text{SUP}} - V_{\text{CC}}$, $I_{\text{CC}} = 70\text{ mA}$;		300	600	mV
V_{DROP}	Dropout voltage (3.3 V LDO)	$V_{\text{SUP}} - V_{\text{CC}}$, $I_{\text{CC}} = 70\text{ mA}$;		350	700	mV
UV_{CC5R}	Under voltage 5 V V_{CC} threshold	Ramp Up		4.7	4.86	V
UV_{CC5F}	Under voltage 5 V V_{CC} threshold	Ramp Down	4.2	4.45		V
UV_{CC33R}	Under voltage 3.3 V V_{CC} threshold ⁽²⁾	Ramp Up		2.9	3.1	V
UV_{CC33F}	Under voltage 3.3 V V_{CC} threshold ⁽²⁾	Ramp Down	2.5	2.75		V
$t_{\text{DET}}(UV_{\text{CC}})$	VCC undervoltage deglitch time. An UV_{CC} event will not be recognized unless it last longer than this. ⁽²⁾	$C_{\text{nRST}} = 20\text{ pF}$	1		15	μs
I_{CCOUT}	Output current	V_{CC} in regulation with 12 V V_{SUP}	0		70	mA
I_{CCOUTL}	Output current limit	V_{CC} short to ground			275	mA
PSRR	Power supply rejection ripple rejection	$V_{\text{RIP}} = 0.5\text{ V}_{\text{PP}}$, Load = 10 mA, $f = 100\text{ Hz}$, CO = 10 μF		60		dB
T_{SDR}	Thermal shutdown temperature	Internal junction temperature - rising	165			$^{\circ}\text{C}$
T_{SDF}	Thermal shutdown temperature	Internal junction temperature - falling			150	$^{\circ}\text{C}$
T_{SDHYS}	Thermal shutdown hysteresis			10		$^{\circ}\text{C}$

- (1) RXD pin is an open drain output. In standby mode RXD is pulled low which has the device pulling current through V_{SUP} through the pull-up resistor to V_{CC} . The value of the pull-up resistor impacts the standby mode current. A 10 k Ω resistor value can add as much as 500 μA of current.
- (2) Specified by design

7.7 ELECTRICAL CHARACTERISTICS

parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
RXD OUTPUT TERMINAL (OPEN DRAIN)						
V_{OL}	Output low voltage	Based upon a 2 k Ω to 10 k Ω external pull-up to V_{CC}			0.2	V_{CC}
I_{OL}	Low level output current, open drain	$\text{LIN} = 0\text{ V}$, $\text{RXD} = 0.4\text{ V}$	1.5			mA
I_{LKG}	Leakage current, high-level	$\text{LIN} = V_{\text{SUP}}$, $\text{RXD} = V_{\text{CC}}$	-5	0	5	μA
TXD INPUT TERMINAL						
V_{IL}	Low level input voltage		-0.3		0.8	V
V_{IH}	High level input voltage		2		5.5	V
I_{IH}	High level input leakage current	TXD = high	-5	0	5	μA
R_{TXD}	Internal pull-up resistor value		125	350	800	k Ω
LIN TERMINAL (REFERENCED TO V_{SUP})						
V_{OH}	HIGH level output voltage	$\text{LIN} = \text{recessive}$, TXD = high, $I_{\text{O}} = 0\text{ mA}$, $V_{\text{SUP}} = 5.5\text{ V to }36\text{ V}$	0.85			V_{SUP}

7.7 ELECTRICAL CHARACTERISTICS (continued)

parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{OL}	LOW level output voltage	LIN dominant, TXD = low, $V_{SUP} = 5.5\text{ V}$ to 36 V			0.2	V_{SUP}
$V_{SUP_NON_OP}$	V_{SUP} where impact of recessive LIN bus < 5% (ISO/DIS 17987 Param 11)	TXD & RXD open, $V_{LIN} = 5.5\text{ V}$ to 42 V , Bus Load = $60\text{ k}\Omega$ + diode and $1.1\text{ k}\Omega$ + diode	-0.3		42	V
I_{BUS_LIM}	Limiting current (ISO/DIS 17987 Param 12)	TXD = 0 V, $V_{LIN} = 36\text{ V}$, $R_{MEAS} = 440\text{ }\Omega$, $V_{SUP} = 36\text{ V}$, $V_{BUSdom} < 4.518\text{ V}$; 8-5	40	90	200	mA
$I_{BUS_PAS_dom}$	Receiver leakage current, dominant (ISO/DIS 17987 Param 13)	$V_{LIN} = 0\text{ V}$, $V_{SUP} = 12\text{ V}$ Driver off/recessive, $R_{MEAS} = 499\text{ }\Omega$; 8-6	-1			mA
$I_{BUS_PAS_rec1}$	Receiver leakage current, recessive (ISO/DIS 17987 Param 14)	$V_{LIN} \geq V_{SUP}$, $5.5\text{ V} \leq V_{SUP} \leq 36\text{ V}$ Driver off, $R_{MEAS} = 1\text{ k}\Omega$; 8-7			20	μA
$I_{BUS_PAS_rec2}$	Receiver leakage current, recessive (ISO/DIS 17987 Param 14)	$V_{LIN} = V_{SUP}$, Driver off, $R_{MEAS} = 1\text{ k}\Omega$; 8-7	-8		8	μA
$I_{BUS_NO_GND}$	Leakage current, loss of ground (ISO/DIS 17987 Param 15)	$GND = V_{SUP}$, $V_{SUP} = 12\text{ V}$, $0\text{ V} \leq V_{LIN} \leq 28\text{ V}$, $R_{MEAS} = 1\text{ k}\Omega$; 8-8	-1		1	mA
$I_{BUS_NO_BAT}$	Leakage current, loss of supply (ISO/DIS 17987 Param 16)	$0\text{ V} \leq V_{LIN} \leq 28\text{ V}$, $V_{SUP} = GND$, $R_{MEAS} = 10\text{ k}\Omega$; 8-9			8	μA
V_{BUSdom}	Low level input voltage (ISO/DIS 17987 Param 17)	LIN dominant (including LIN dominant for wake up); 8-3 , 8-4			0.4	V_{SUP}
V_{BUSrec}	High level input voltage (ISO/DIS 17987 Param 18)	LIN recessive; 8-3 , 8-4	0.6			V_{SUP}
V_{BUS_CNT}	Receiver center threshold (ISO/DIS 17987 Param 19)	$V_{BUS_CNT} = (V_{IL} + V_{IH})/2$; 8-3 , 8-4	0.475	0.5	0.525	V_{SUP}
V_{HYS}	Hysteresis voltage (ISO/DIS 17987 Param 20)	$V_{HYS} = (V_{IL} - V_{IH})$; 8-3 , 8-4			0.175	V_{SUP}
V_{SERIAL_DIODE}	Serial diode LIN term pull-up path (ISO/DIS 17987 Param 21)	By design and characterization	0.4	0.7	1.0	V
$R_{RESPONDER}$	Pull-up resistor to V_{SUP} (ISO/DIS 17987 Param 26)	Normal and Standby modes	20	45	60	k Ω
I_{RSLEEP}	Pull-up current source to V_{SUP}	Sleep mode, $V_{SUP} = 12\text{ V}$, LIN = GND	-20		-2	μA
C_{LIN_PIN}	Capacitance of the LIN pin				55	pF
EN INPUT TERMINAL						
V_{IH}	High level input voltage		2		5.5	V
V_{IL}	Low level input voltage		-0.3		0.8	V
V_{HYS}	Hysteresis voltage	By design and characterization	30		500	mV
I_{IL}	Low level input current	EN = Low	-5	0	5	μA
R_{EN}	Internal pull-down resistor		125	350	800	k Ω
I_{LKG}	Leakage current, high-level	LIN = V_{SUP} , nRST = V_{CC}	-5		5	μA
V_{OL}	Low-level output voltage	Based upon external pull up to V_{CC}			0.2	V_{CC}
I_{OL}	Low-level output current, open drain	LIN = 0 V, nRST = 0.4 V	1.5			mA
DUTY CYCLE CHARACTERISTICS⁽¹⁾						
D1 _{12V}	Duty Cycle 1 (ISO/DIS 17987 Param 27)	$TH_{REC(MAX)} = 0.744 \times V_{SUP}$, $TH_{DOM(MAX)} = 0.581 \times V_{SUP}$, $V_{SUP} = 5.5\text{ V}$ to 18 V , $t_{BIT} = 50\text{ }\mu\text{s}$ (20 kbps), $D1 = t_{BUS_rec(min)}/(2 \times t_{BIT})$ (See 8-10 , 8-11)	0.396			
D2 _{12V}	Duty Cycle 2 (ISO/DIS 17987 Param 28)	$TH_{REC(MIN)} = 0.422 \times V_{SUP}$, $TH_{DOM(MIN)} = 0.284 \times V_{SUP}$, $V_{SUP} = 5.5\text{ V}$ to 18 V , $t_{BIT} = 50\text{ }\mu\text{s}$ (20 kbps), $D2 = t_{BUS_rec(MAX)}/(2 \times t_{BIT})$ (See 8-10 , 8-11)			0.581	
D3 _{12V}	Duty Cycle 3 (ISO/DIS 17987 Param 29)	$TH_{REC(MAX)} = 0.778 \times V_{SUP}$, $TH_{DOM(MAX)} = 0.616 \times V_{SUP}$, $V_{SUP} = 5.5\text{ V}$ to 18 V , $t_{BIT} = 96\text{ }\mu\text{s}$ (10.4 kbps), $D3 = t_{BUS_rec(min)}/(2 \times t_{BIT})$ (See 8-10 , 8-11)	0.417			

7.7 ELECTRICAL CHARACTERISTICS (continued)

parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
D4 _{12V}	Duty Cycle 4 (ISO/DIS 17987 Param 30) TH _{REC(MIN)} = 0.389 x V _{SUP} , TH _{DOM(MIN)} = 0.251 x V _{SUP} , V _{SUP} = 5.5 V to 18 V, t _{BIT} = 96 μs (10.4 kbps), D4 = t _{BUS_rec(MAX)} /(2 x t _{BIT}) (See 8-10 , 8-11)			0.59	

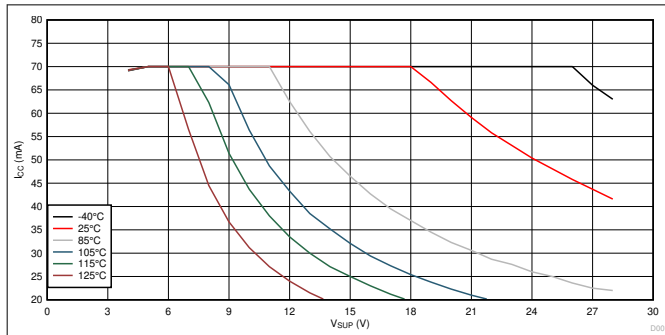
(1) See errata [TLIN1028S-Q1 Duty Cycle Over V_{SUP}](#)

7.8 AC SWITCHING CHARACTERISTICS

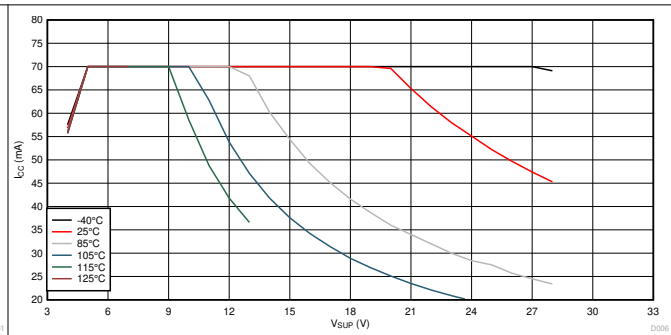
parameters valid over $-40^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$ range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DEVICE SWITCHING CHARACTERISTICS					
t _{rx_pdr} t _{rx_pdf}	Receiver rising/falling propagation delay time (ISO/DIS 17987 Param 31) R _{RXD} = 2.4 kΩ, C _{RXD} = 20 pF (See 8-12 , 8-13 and 8-17)			6	μs
t _{rx_sym}	Symmetry of receiver propagation delay time Receiver rising propagation delay time (ISO/DIS 17987 Param 32) Rising edge with respect to falling edge, (t _{rx_sym} = t _{rx_pdf} - t _{rx_pdr}), R _{RXD} = 2.4 kΩ, C _{RXD} = 20 pF (8-12 , 8-13 and 8-17)	-2		2	μs
t _{LINBUS}	LIN wakeup time (minimum dominant time on LIN bus for wakeup) See 8-16 , 9-3 and 9-4	25	100	150	μs
t _{CLEAR}	Time to clear false wakeup prevention logic if LIN bus had a bus stuck dominant fault (recessive time on LIN bus to clear bus stuck dominant fault) See 9-4	8	17	50	μs
t _{TXD_DTO}	Dominant state time out	20	34	80	ms
t _{EN}	Enable pin deglitch time Time enable pin state change before initiating mode change or sampling TXD pin: See 8-14	3		12	μs
t _{MODE_CHANGE}	Mode change delay time normal mode to sleep or standby mode Time to change from normal mode to sleep or standby after TXD pin sampling after EN pin set low: See 8-14			20	μs
t _{MODE_CHANGE}	Mode change delay time sleep mode to normal mode Time to change from sleep mode to normal mode through EN pin and not due to a wake event; RXD pulled up to V _{CC} : See 8-14			400	μs
t _{NOMINT}	Normal mode initialization time Time for normal mode to initialize and data on RXD pin to be valid after t _{EN} See 8-14			35	μs
t _{PWR}	Power up time Upon power up time it takes for valid data on RXD			1.5	ms

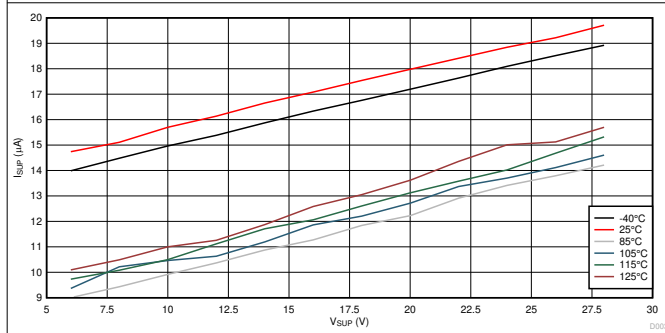
7.9 Typical Characteristics



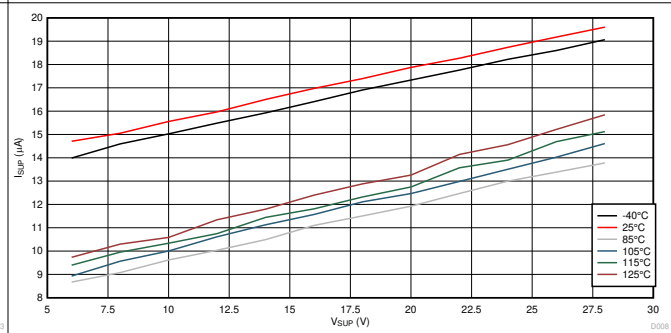
7-1. I_{CC} vs V_{SUP} vs Temperature



7-2. I_{CC} vs V_{SUP} vs Temperature



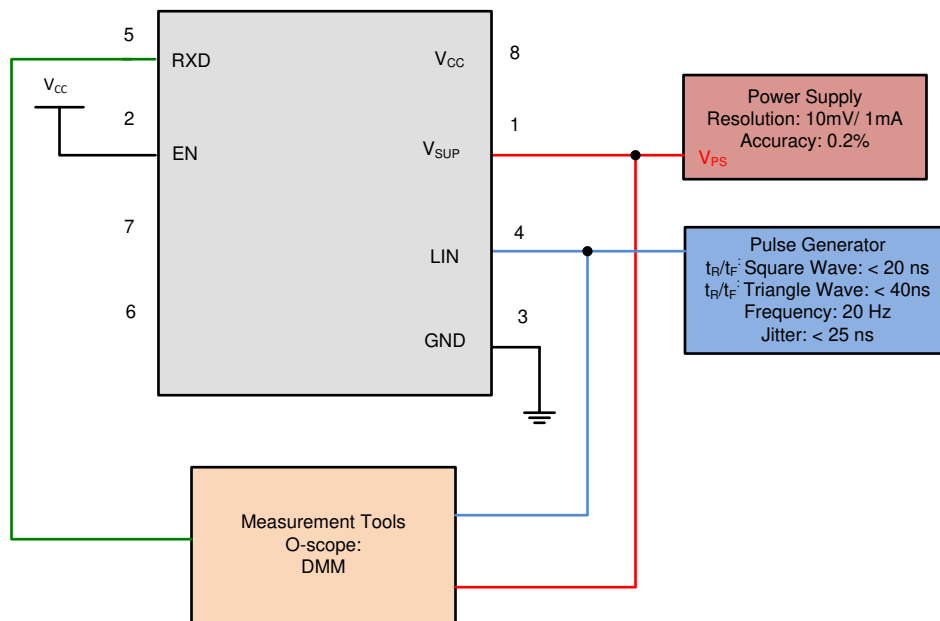
7-3. Sleep Mode Current Across V_{SUP} and Temperature



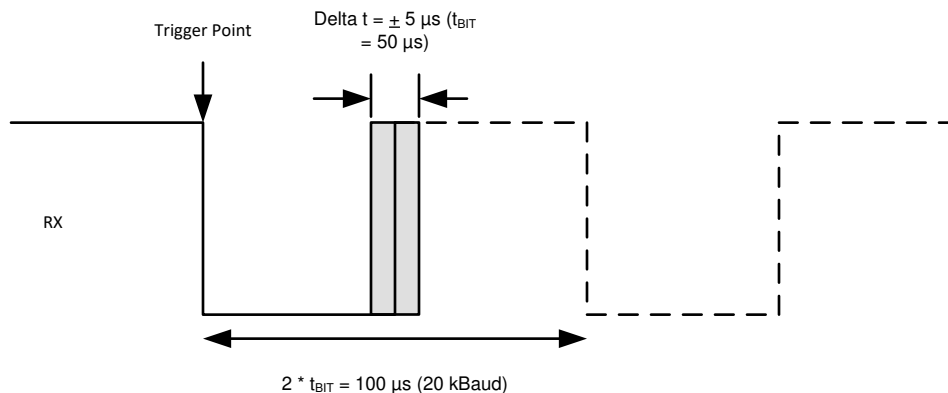
7-4. Sleep Mode Current Across V_{SUP} and Temperature

8 Parameter Measurement Information

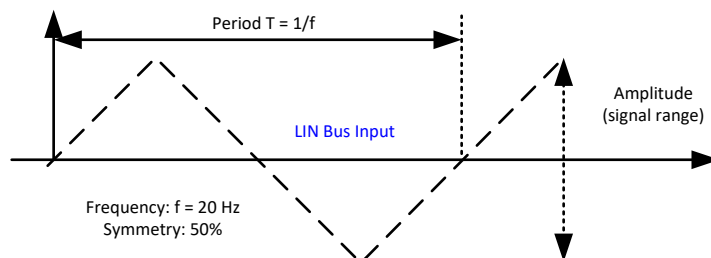
8.1 Test Circuit: Diagrams and Waveforms



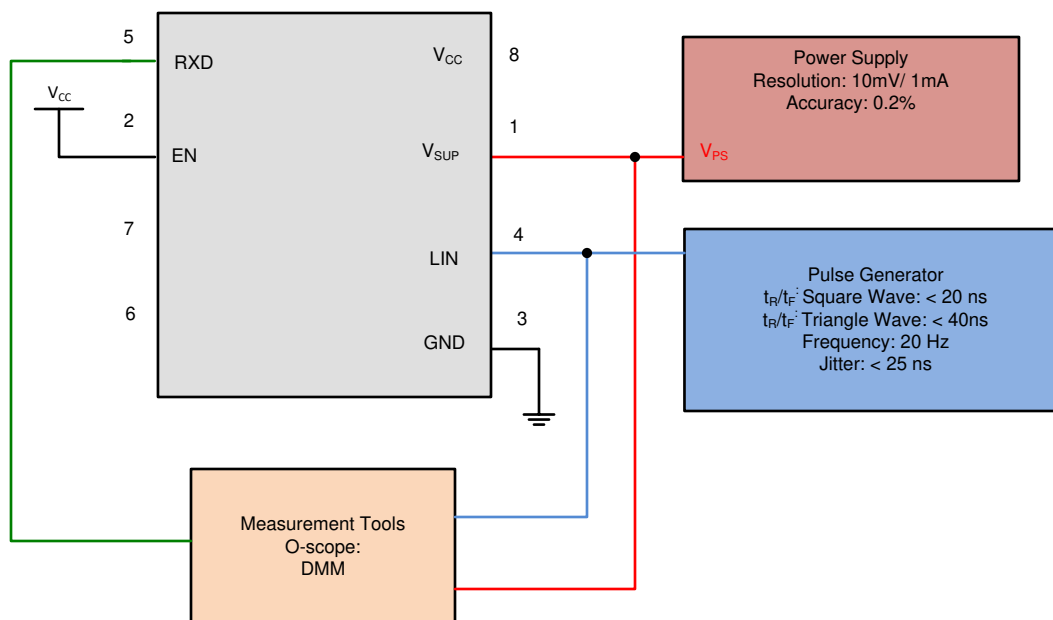
8-1. Test System: Operating Voltage Range with RX and TX Access



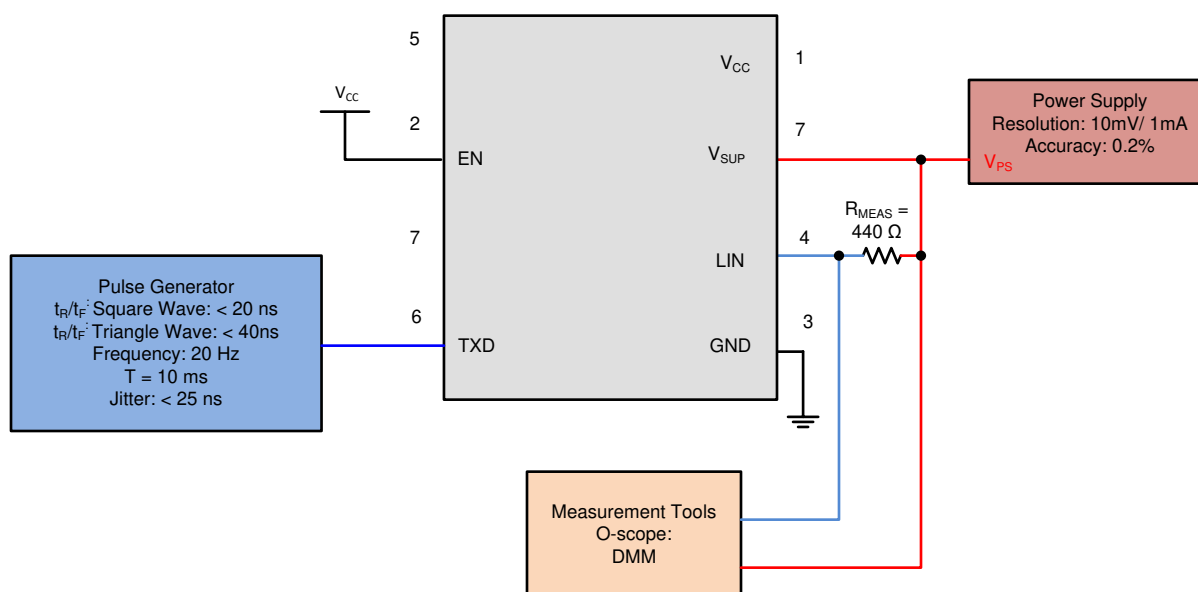
8-2. RX Response: Operating Voltage Range



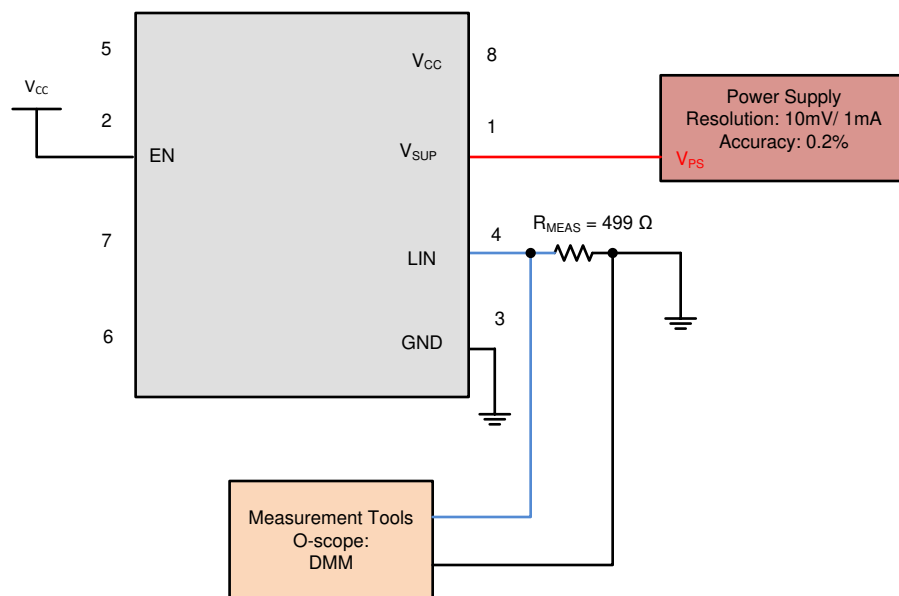
8-3. LIN Bus Input Signal



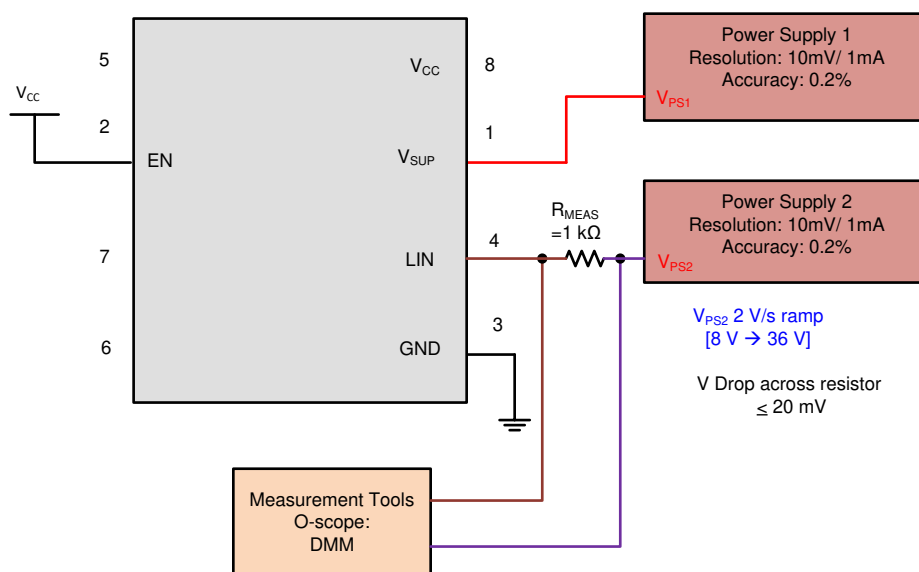
8-4. LIN Receiver Test with RX access



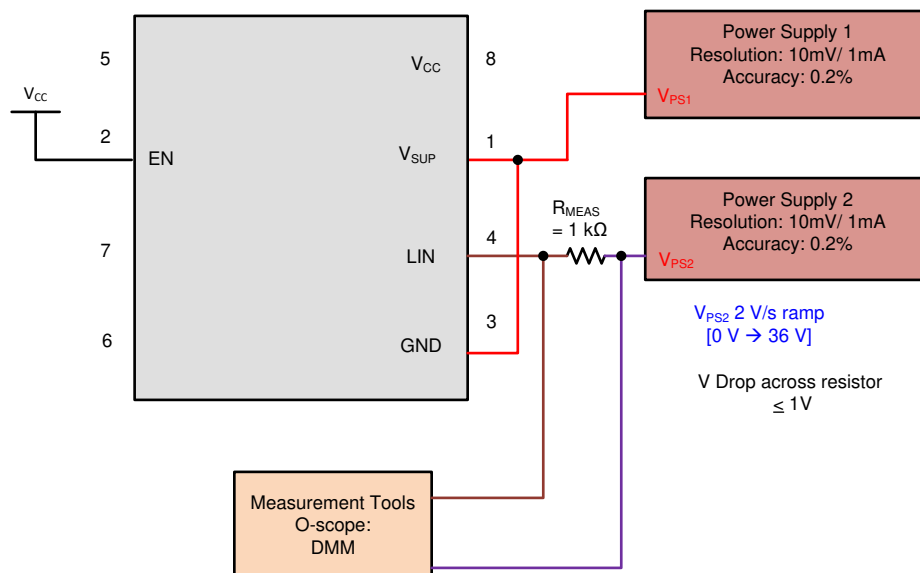
8-5. Test Circuit for I_{BUS_LIM} at Dominant State (Driver on)



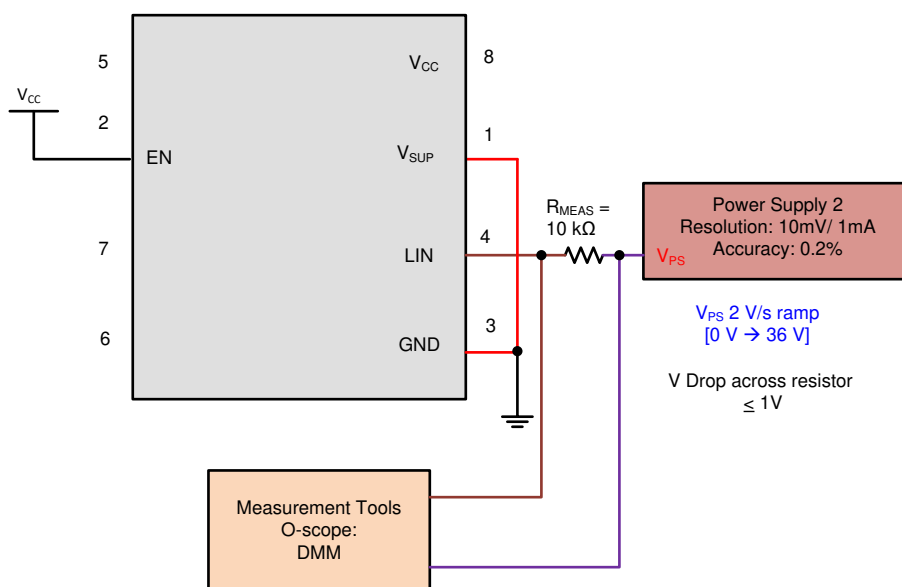
8-6. Test Circuit for $I_{BUS_PAS_dom}$; TXD = Recessive State $V_{BUS} = 0$ V



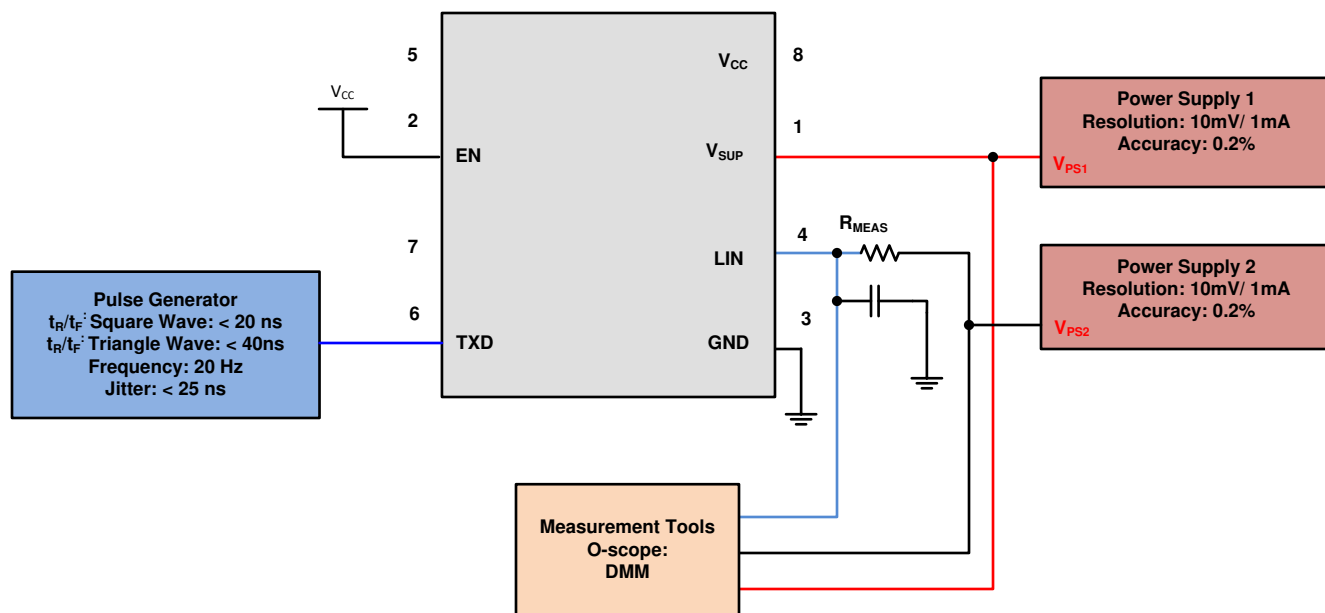
8-7. Test Circuit for $I_{BUS_PAS_rec}$



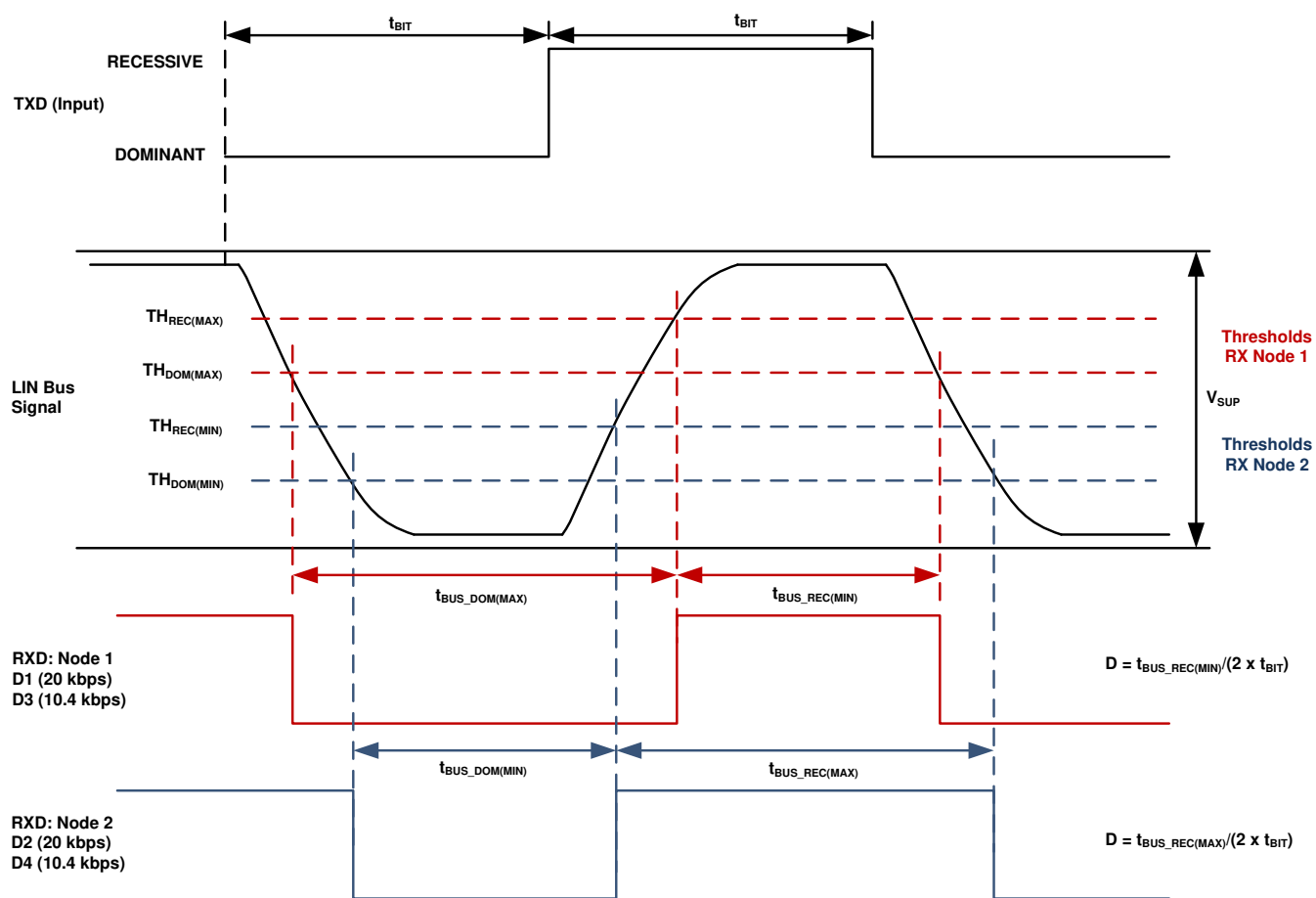
8-8. Test Circuit for $I_{BUS_NO_GND}$ Loss of GND



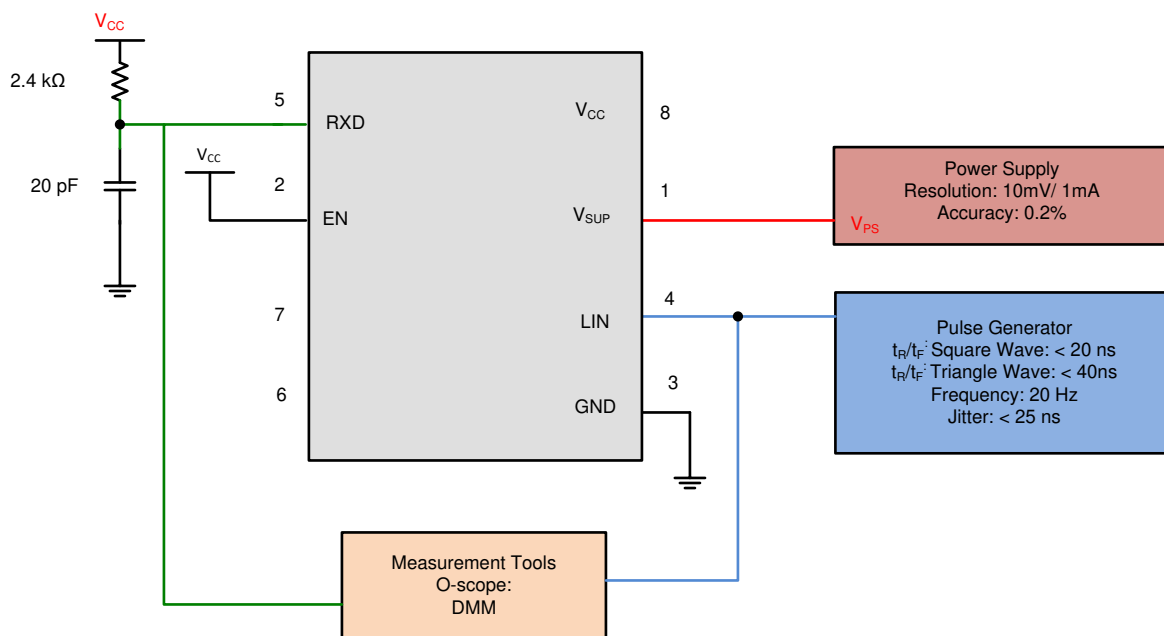
8-9. Test Circuit for $I_{BUS_NO_BAT}$ Loss of Battery



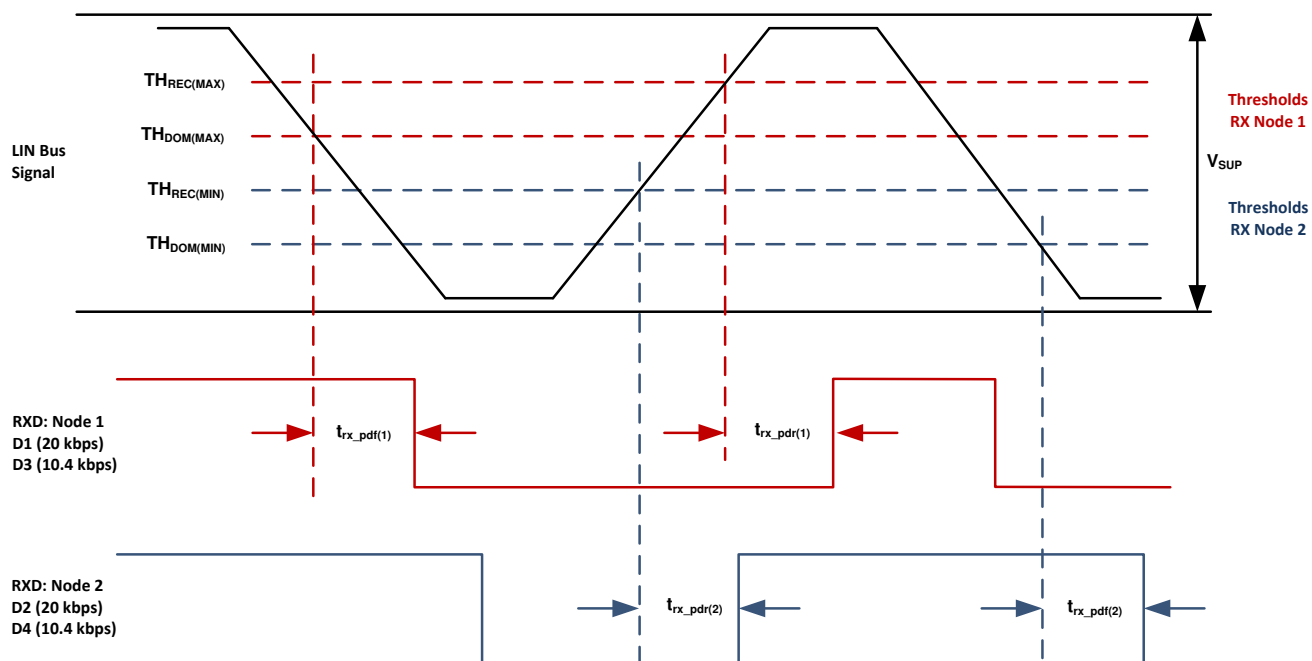
8-10. Test Circuit Slope Control and Duty Cycle



8-11. Definition of Bus Timing

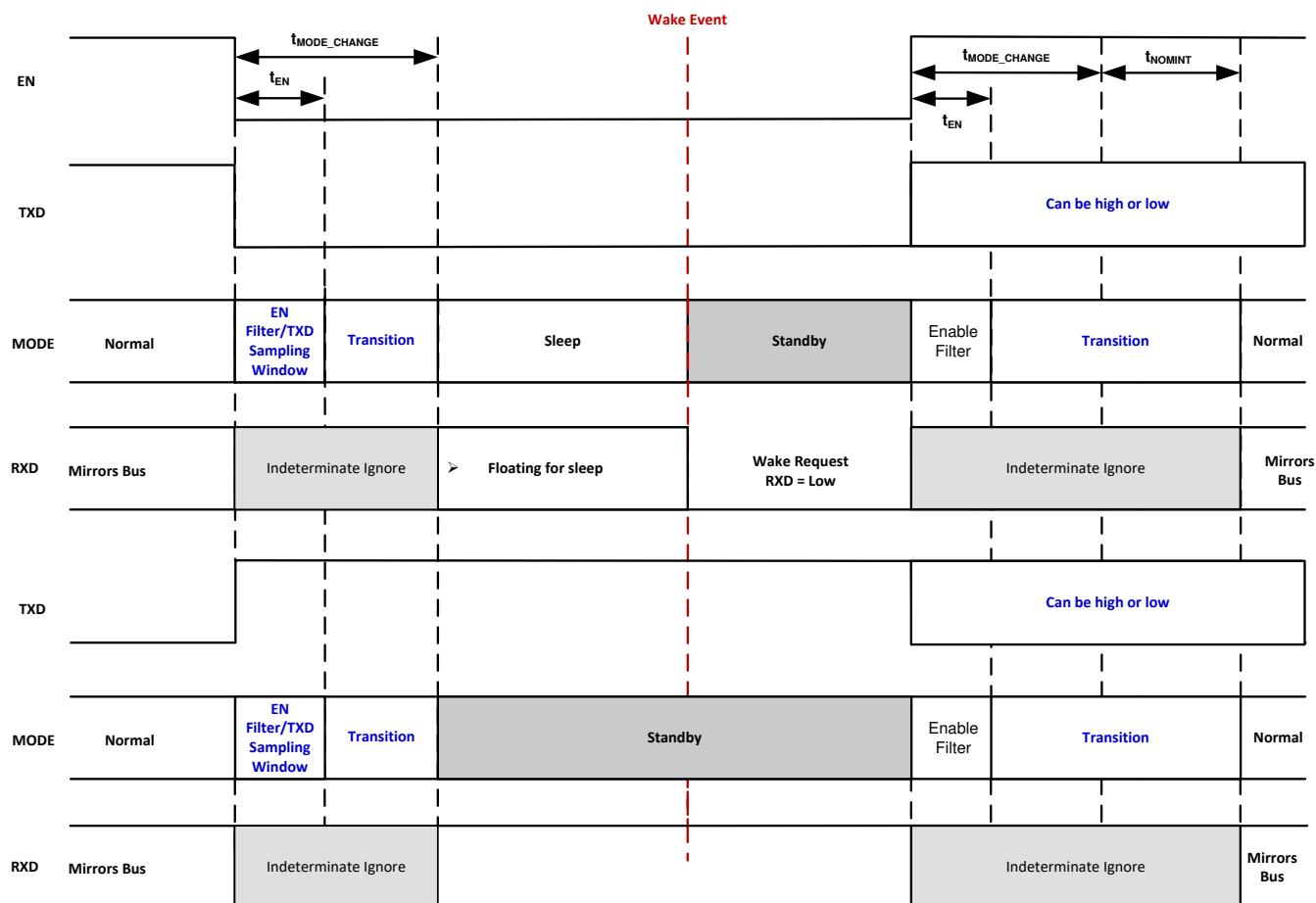


8-12. Propagation Delay Test Circuit

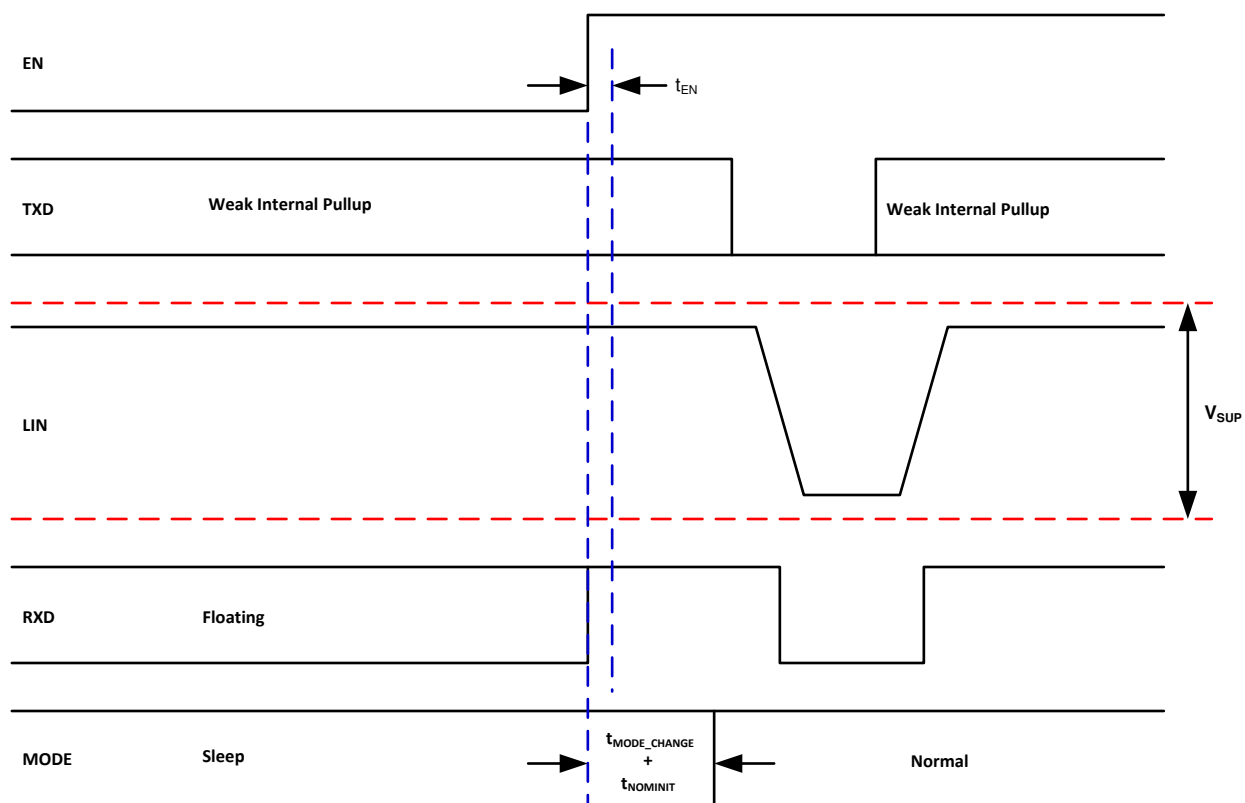


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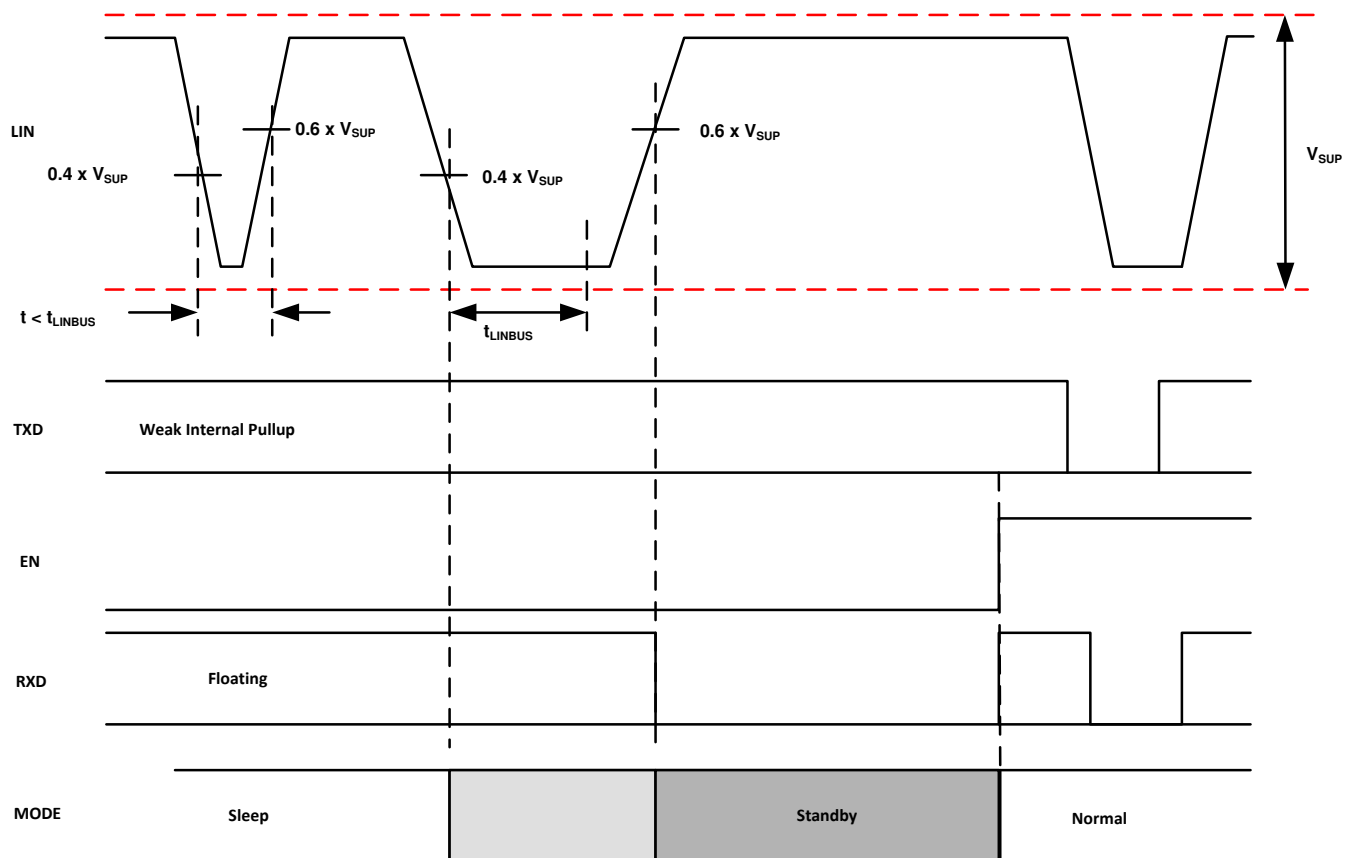
8-13. Propagation Delay



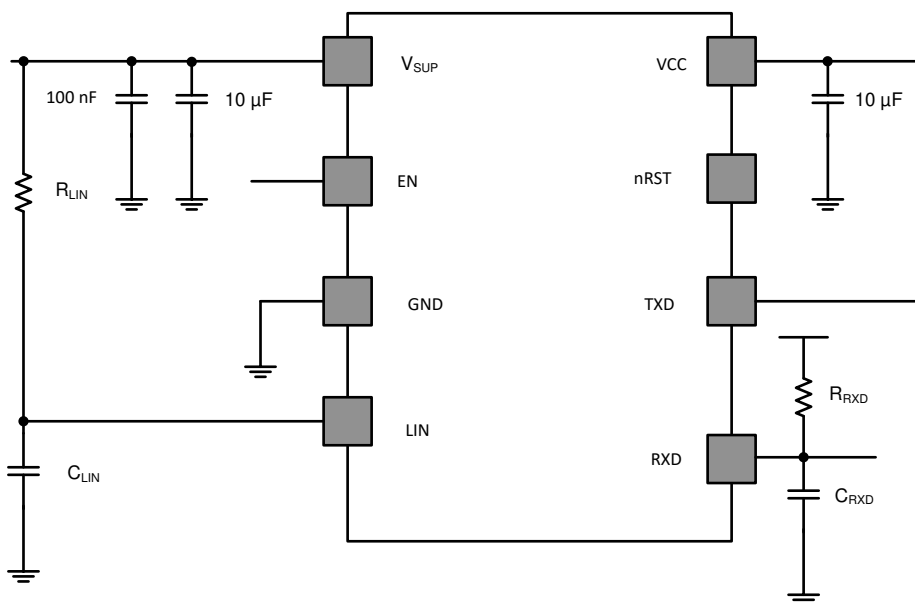
8-14. Mode Transitions



8-15. Wakeup Through EN



8-16. Wakeup through LIN



8-17. Test Circuit for AC Characteristics

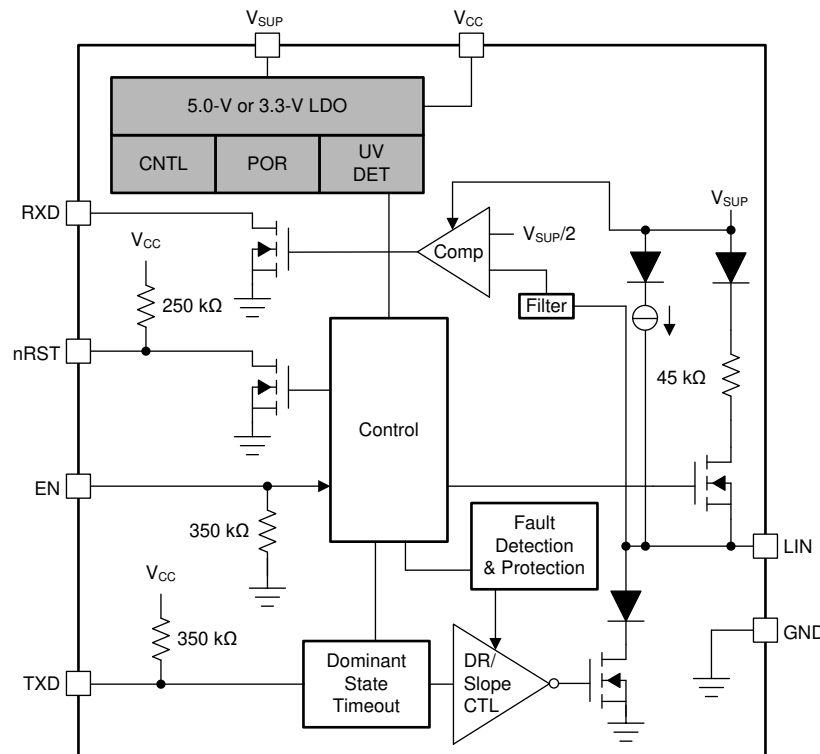
9 Detailed Description

9.1 Overview

The TLIN1028S-Q1 LIN transceiver is a Local Interconnect Network (LIN) physical layer transceiver, compliant to LIN 2.0, LIN 2.1, LIN 2.2, LIN 2.2A and ISO/DIS 17987-4 with integrated wake-up and protection features. The LIN bus is a single-wire, bidirectional bus that typically is used in low-speed in-vehicle networks with data rates that range up to 20 kbps. The LIN receiver works up to 100 kbps supporting in-line programming. The device converts the LIN protocol data stream on the TXD input into a LIN bus signal using a current-limited wave-shaping driver which reduces electromagnetic emissions (EME). The receiver converts the data stream to logic-level signals that are sent to the microprocessor through the open-drain RXD pin. The LIN bus has two states: dominant state (voltage near ground) and recessive state (voltage near battery). In the recessive state, the LIN bus is pulled high by the internal pull-up resistor (45 kΩ) and a series diode.

Ultra-low current consumption is possible using the sleep mode. The TLIN1028S-Q1 provides two methods to wake up from sleep mode: EN pin and LIN bus. The device integrates a low dropout voltage regulator with a wide input from V_{SUP} providing 5 V $\pm 2\%$ or 3.3 V $\pm 2\%$ with up to 70 mA of current depending upon system implementation. nRST is asserted high when V_{CC} increases above UV_{CC} and stays high as long as V_{CC} is above this threshold.

9.2 Functional Block Diagram



9-1. Functional Block Diagram

9.3 Feature Description

9.3.1 LIN Pin

This high-voltage input or output pin is a single-wire LIN bus transmitter and receiver. The LIN pin can survive transient voltages up to 58 V. Reverse currents from the LIN to supply (V_{SUP}) are minimized with blocking diodes, even in the event of a ground shift or loss of supply (V_{SUP}).

9.3.1.1 LIN Transmitter Characteristics

The transmitter meets thresholds and AC parameters according to the LIN specification. The transmitter is a low-side transistor with internal current limitation and thermal shutdown. During a thermal shutdown condition, the transmitter is disabled to protect the device. There is an internal pull-up resistor with a serial diode structure to V_{SUP} , so no external pull-up components are required for the LIN responder node applications. An external pull-up resistor and series diode to V_{SUP} must be added when the device is used for a commander node application.

9.3.1.2 LIN Receiver Characteristics

The receiver characteristic thresholds are ratio-metric with the device supply pin according to the LIN specification.

The receiver is capable of receiving higher data rates (> 100 kbps) than supported by LIN or SAEJ2602 specifications. This allows the TLIN1028S-Q1 to be used for high-speed downloads at the end-of-line production or other applications. The actual data rate achievable depends on system time constants (bus capacitance and pull-up resistance) and driver characteristics used in the system.

9.3.1.2.1 Termination

There is an internal pull-up resistor with a serial diode structure to V_{SUP} , so no external pull-up components are required for the LIN responder node applications. An external pull-up resistor ($1\text{ k}\Omega$) and a series diode to V_{SUP} must be added when the device is used for commander node applications as per the LIN specification.

Figure 9-2 shows a commander node configuration and how the voltage levels are defined

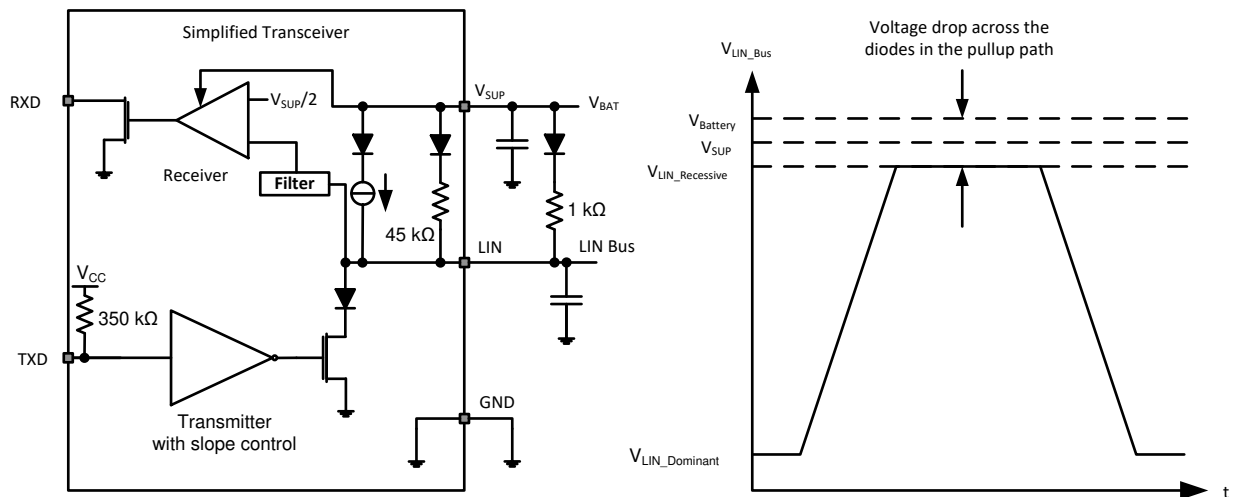


Figure 9-2. Commander Node Configuration with Voltage Levels

9.3.2 TXD (Transmit Input)

TXD is the interface to the node processor's LIN protocol controller that is used to control the state of the LIN output. When TXD is low, the LIN output is dominant (near ground). When TXD is high, the LIN output is recessive (near V_{SUP}). See Figure 9-2. The TXD input structure is compatible with processors that use 3.3 V and 5 V V_I and V_O . TXD has an internal pull-up resistor. The LIN bus is protected from being stuck dominant through a system failure driving TXD low through the dominant state time-out timer.

9.3.3 RXD (Receive Output)

RXD is the interface to the processor's LIN protocol controller, which reports the state of the LIN bus voltage. LIN recessive (near V_{SUP}) is represented by a high level on the RXD and LIN dominant (near ground) is represented by a low level on the RXD pin. The RXD output structure is an open-drain output stage. This allows the device to be used with 3.3 V and 5 V $V_{I/O}$ processors. If the processor's RXD pin does not have an integrated pull-up, an external pull-up resistor to the processors I and O supply voltage is required. In standby mode, the RXD pin is driven low to indicate a wake-up request from the LIN bus from sleep mode. When going from normal mode to

standby mode, the RXD pin is released and pulled-up to the voltage rail that the external pull-up resistor is connected. A LIN bus wake event will cause the RXD pin to be pulled low indicating a wake request.

9.3.4 V_{SUP} (Supply Voltage)

V_{SUP} is the power supply pin. V_{SUP} is connected to the battery through an external reverse-battery blocking diode.

The V_{SUP} pin is a high-voltage-tolerant pin. A decoupling capacitor with a value of 100 nF is recommended to be connected close to this pin to improve the transient performance. If there is a loss of power at the ECU level, the device has ultra low leakage from the LIN pin, which does not load the bus down. This is optimal for LIN systems in which some of the nodes are unpowered (ignition supplied) while the rest of the network remains powered (battery supplied). When V_{SUP} drops low enough the regulated output drops out of regulation. The LIN bus works with a V_{SUP} as low as 5.5 V, but at a lower voltage, the performance is indeterminate and not ensured. If V_{SUP} voltage level drops enough, it triggers the UV_{SUP}, and if it keeps dropping, at some point it passes the POR threshold.

9.3.5 GND (Ground)

GND is the device ground connection. The device can operate with a ground shift as long as the ground shift does not reduce the V_{SUP} below the minimum operating voltage. If there is a loss of ground at the ECU level, the device has ultra low leakage from the LIN pin, which does not load the bus down. This is optimal for LIN systems in which some of the nodes are unpowered (ignition supplied) while the rest of the network remains powered (battery supplied).

9.3.6 EN (Enable Input)

EN controls the operational modes of the device. When EN is high, the device is in normal operating mode allowing a transmission path from TXD to LIN and from LIN to RXD. When EN is low, the device is put into sleep or standby mode and there are no transmission paths available. EN has an internal pull-down resistor to ensure the device remains in low power mode even if EN is left floating. EN should be held low until V_{SUP} reaches the expected system voltage level.

9.3.7 nRST (Reset Output)

The V_{CC} pin is monitored for under voltage events. This pin is internally pulled up to V_{CC} and when an undervoltage event takes place, this pin is pulled low. The pin returns to V_{CC} once the voltage on V_{CC} exceeds the under-voltage threshold. nRST is dependent on the value V_{CC} and not the operational mode. If UV_{CC} takes place for longer than t_{DET(UVCC)} nRST is pulled to ground. If a thermal shutdown event takes place, this pin is pulled to ground.

9.3.8 V_{CC} (Supply Output)

The V_{CC} terminal can provide 5 V or 3.3 V with up to 70 mA to power up external devices when using high-k boards and thermal management best practices .

9.3.9 Protection Features

The device has several protection features that are described as follows.

9.3.9.1 TXD Dominant Time Out (DTO)

During normal mode, if TXD is inadvertently driven permanently low by a hardware or software application failure, the LIN bus is protected by the dominant state time-out timer. This timer is triggered by a falling edge on the TXD pin. If the low signal remains on TXD for longer than t_{TXD.DTO}, the transmitter is disabled, thus allowing the LIN bus to return to recessive state and communication to resume on the bus. The protection is cleared and the t_{TXD.DTO} timer is reset by a rising edge on TXD. The TXD pin has an internal pull-up to ensure the device fails to a known recessive state if TXD is disconnected. During this fault, the transceiver remains in normal mode (assuming no change of state request on EN), the RXD pin reflects the LIN bus and the LIN bus pull-up termination remains on.

9.3.9.2 Bus Stuck Dominant System Fault: False Wake Up Lockout

The device contains logic to detect bus stuck dominant system faults and prevents the device from waking up falsely during the system fault. Upon entering sleep mode, the device detects the state of the LIN bus. If the bus is dominant, the wake-up logic is locked out until a valid recessive on the bus “clears” the bus stuck dominant, preventing excessive current use. [Figure 9-3](#) and [Figure 9-4](#) show the behavior of this protection.

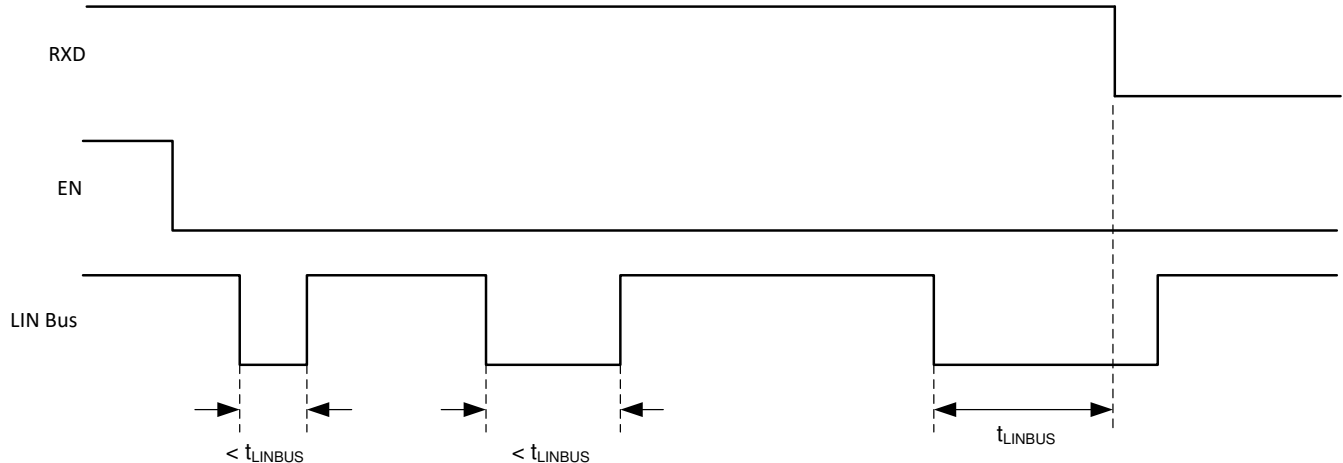


Figure 9-3. No Bus Fault: Entering Sleep Mode with Bus Recessive Condition and Wakeup

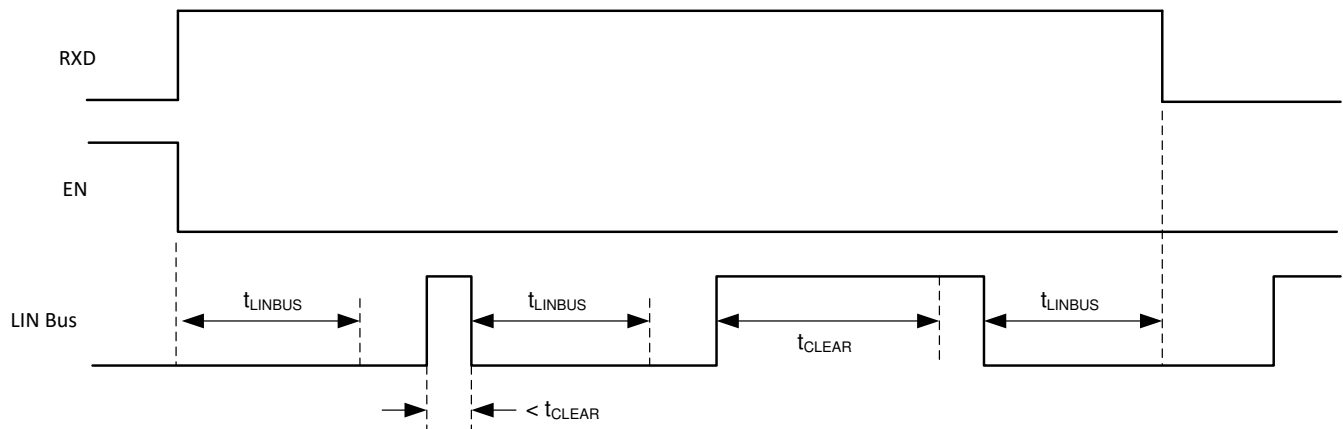


Figure 9-4. Bus Fault: Entering Sleep Mode with Bus Stuck Dominant Fault, Clearing, and Wakeup

9.3.9.3 Thermal Shutdown

The LIN transmitter is protected by current-limiting circuit; however, if the junction temperature of the device exceeds the thermal shutdown threshold, the device puts the LIN transmitter into the recessive state and turns off the V_{CC} regulator. The nRST pin is pulled to ground during a TSD event. Once the over-temperature fault condition has been removed and the virtual junction temperature has cooled beyond the hysteresis temperature, the transmitter is re-enabled. During this fault the device enters a TSD off mode. Once the junction temperature cools, the device enters standby mode as per the state diagram.

9.3.9.4 Under Voltage on V_{SUP}

The device contains a power-on reset circuit to avoid false bus messages during under voltage conditions when V_{SUP} is less than UV_{SUP} .

9.3.9.5 Unpowered Device and LIN Bus

In automotive applications, some LIN nodes in a system can be unpowered (ignition supplied) while others in the network remain powered by the battery. The device has extremely low unpowered leakage current from the bus, so an unpowered node does not affect the network nor load it down.

9.4 Device Functional Modes

nRST: Float

The TLIN1028S-Q1 has three functional modes of operation: normal, sleep, and standby. The next sections describes these modes as well as how the device moves between the different modes. [图 9-5](#) graphically shows the relationship while [表 9-1](#) shows the state of pins.

表 9-1. Operating Modes

Mode	EN	RXD	LIN BUS Termination	Transmitter	nRST	Comment
Sleep	Low	Floating	Weak Current pull-up	Off	Ground	nRST is internally connected to the LDO output which is pulled to ground in sleep mode.
Standby Init	Low	Floating	45 k Ω (typical)	Off	Ramping	nRST is internally connected to the LDO output which in standby init mode is pulled low until VCC raises beyond UV _{CC} threshold.
Standby from SLP	Low	Low	45 k Ω (typical)	Off	V _{CC}	Wake-up event detected, waiting on processors to set EN nRST comes on to V _{CC} once thresholds are met.
Standby from Norm	Low	High	45 k Ω (typical)	Off	V _{CC}	LDO is on and RXD is high
Normal	High	LIN Bus Data	45 k Ω (typical)	On	V _{CC}	LIN transmission up to 20 kbps
TSD Off	NA	Floating	45 k Ω (typical)	Off	Ground	nRST is pulled low as the LDO is turned off which means UV _{CC} threshold has been met.

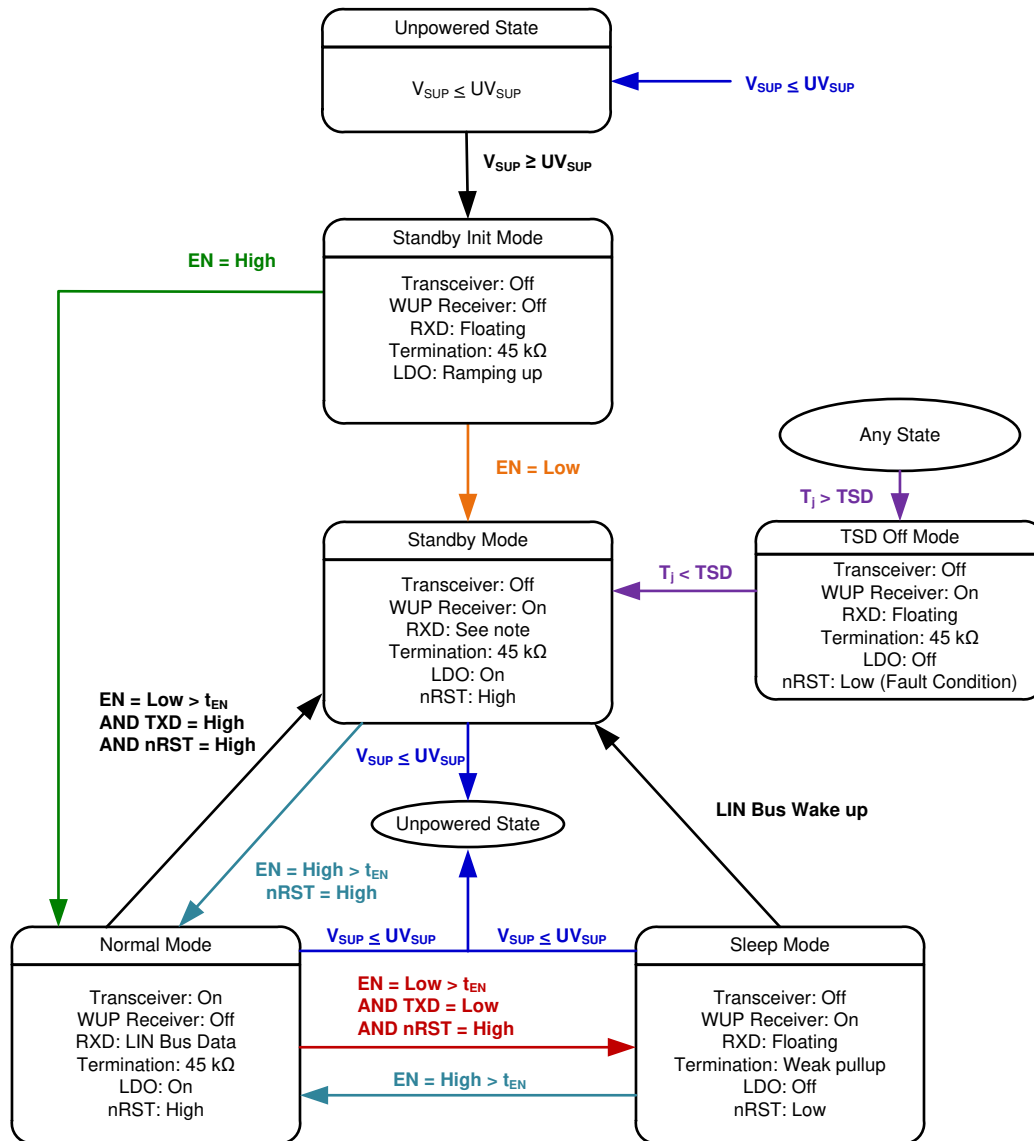


图 9-5. Operating State Diagram

注

- RXD is latched low due to a wake event from sleep mode once entering standby mode
- RXD is high when entering standby mode from other modes and is not latch low for a wake event

9.4.1 Normal Mode

If the EN pin is high after the device enters standby init mode it enters normal mode. If EN is low, it enters standby mode. In normal operational mode, the receiver and transmitter are active and the LIN transmission up to the LIN specified maximum of 20 kbps is supported. The receiver detects the data stream on the LIN bus and outputs it on RXD for the LIN controller. A recessive signal on the LIN bus is a digital high and a dominant signal on the LIN bus is a digital low. The driver transmits input data from TXD to the LIN bus. Normal mode is entered as EN transitions high while the device is in sleep or standby mode for $> t_{EN}$. Once EN has been high for t_{EN} the device enters normal mode after t_{MODE_CHANGE} and $t_{NOMINIT}$.

9.4.2 Sleep Mode

While the device is in sleep mode, the following conditions exist:

- The LIN bus driver is disabled and the internal LIN bus termination is switched off (to minimize power loss if LIN is short-circuited to ground). However, the weak current pull-up is active to prevent false wake-up events in case an external connection to the LIN bus is lost.
- The normal receiver is disabled.
- EN input and LIN wake-up receiver are active.

9.4.3 Standby Mode

Standby mode is entered either by a wake up event through LIN bus while the device is in sleep mode or by the EN pin from normal or standby init modes. From normal mode EN must be low for $> t_{EN}$ and TXD and nRST are high. RXD pin in standby mode is dependent upon how standby mode was entered. If entered from normal mode or power up, RXD is high. If entered from sleep mode, RXD is pulled low to indicate a wake event.

During power up, if EN is low the device goes into standby mode, and if EN is high, the device goes into normal mode. EN has an internal pull-down resistor ensuring EN is pulled low if the pin is left floating in the system.

9.4.4 Wake-Up Events

There are ways to wake-up from sleep mode:

- Remote wake-up initiated by the falling edge of a recessive (high) to dominant (low) state transition on the LIN bus where the dominant state is held for the t_{LINBUS} filter time. After this t_{LINBUS} filter time has been met and a rising edge on the LIN bus going from dominant state to recessive state initiates a remote wake-up event eliminating false wake ups from disturbances on the LIN bus or if the bus is shorted to ground.
- Local wake-up through EN being set high for longer than .

9.4.4.1 Wake-Up Request (RXD)

When the TLIN1028S-Q1 encounters a wake-up event from the LIN bus, RXD goes low and the device transitions to standby mode until EN is reasserted high and the device enters normal mode. Once the device enters normal mode, the RXD pin releases the wake-up request signal and the RXD pin then reflects the receiver output from the LIN bus.

9.4.5 Mode Transitions

When the device is transitioning between modes, the device needs the time t_{MODE_CHANGE} and t_{NOMINT} to allow the change to fully propagate from the EN pin through the device into the new state.

9.4.6 Voltage Regulator

The device has an integrated high-voltage LDO that operates over a 5.5 V to 28 V input voltage range for both 3.3 V and 5 V V_{CC} . The device has an output current capability of 70 mA and support fixed output voltages of 3.3 V (TLIN10283S-Q1) or 5 V (TLIN10285S-Q1). It features thermal shutdown and short-circuit protection to prevent damage during over-temperature and over-current conditions

9.4.6.1 V_{CC}

The V_{CC} pin is the regulated output based on the required voltage. The regulated voltage accuracy is $\pm 2\%$. The output is current limited. In the event that the regulator drops out of regulation, the output tracks the input minus a drop based on the load current. When the input voltage drops below the UV_{SUP} threshold, the regulator shuts down until the input voltage returns above the UV_{SUPR} level. The device monitors situations where V_{CC} may drop below the UV_{CC} level thus causing the nRST pin to be pulled low.

9.4.6.2 Output Capacitance Selection

For stable operation over the full temperature range and with load currents up to 70 mA on V_{CC} a certain capacitance is expected and depends upon the minimum load current. To support no load to full load a value of 10 μF and ESR smaller than 2 Ω is needed. For 500 μA to full load an 1 μF capacitance can be used. The low ESR recommendation is to improve the load transient performance.

9.4.6.3 Low-Voltage Tracking

At low input voltages, the regulator drops out of regulation and the output voltage tracks input minus a voltage based on the load current (IL) and power-switch resistor. This tracking allows for a smaller input capacitance and can possibly eliminate the need for a boost converter during cold-crank conditions.

9.4.6.4 Power Supply Recommendation

The device is designed to operate from an input-voltage supply range between 5.5 V and 28 V. This input supply must be well regulated. If the input supply is located more than a few inches from the device. The recommended minimum capacitance at the pin is 100 nF . The max voltage range is for the LIN functionality. Exceeding 24V for the LDO reduces the effective current sourcing capability due to thermal considerations.

10 Application and Implementation

注

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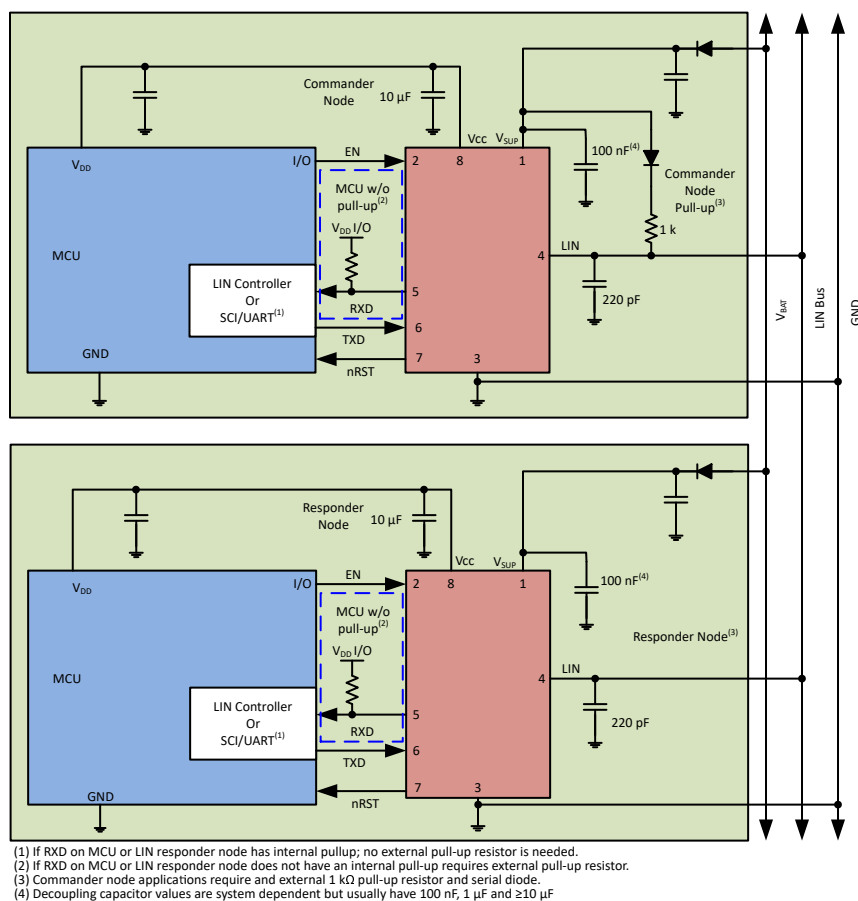
10.1 Application Information

The TLIN1028S-Q1 can be used as both a responder device and a commander device in a LIN network. The device comes with the ability to support a remote wake-up requests. It can provide the power to the local processor.

10.2 Typical Application

The device comes with an integrated 45 k Ω pull-up resistor and series diode for responder node applications. For commander node applications, an external 1 k Ω pull-up resistor with series blocking diode can be used. 

10-1



 10-1. Typical LIN Bus

10.2.1 Design Requirements

10.2.1.1 Normal Mode Application Note

When using the TLIN1028S-Q1 in systems which are monitoring the RXD pin for a wake-up request, special care should be taken during the mode transitions. The output of the RXD pin is indeterminate for the transition period between states as the receivers are switched. The application software should not look for an edge on the RXD pin indicating a wake-up request until $t_{\text{MODE_CHANGE}}$. This is shown in [Figure 8-14](#) when transitioning to normal mode there is an initialization period shown as t_{NOMINIT} .

10.2.1.2 TXD Dominant State Timeout Application Note

The maximum dominant TXD time allowed by the TXD dominant state time out limits the minimum possible data rate of the device. The LIN protocol has different constraints for commander and responder node applications; thus, there are different maximum consecutive dominant bits for each application case and thus different minimum data rates.

10.2.1.3 Brownout

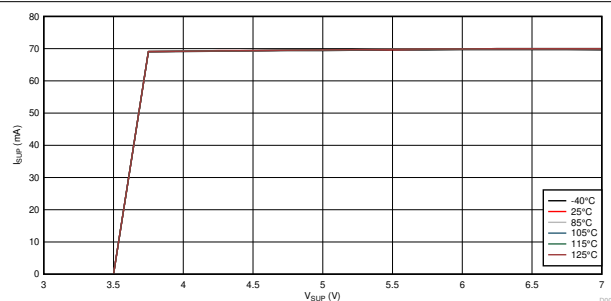
[Figure 10-9](#) and [Figure 10-10](#) show the behavior of the LIN, nRST and V_{CC} pins during a brownout condition. For the TLIN10283S-Q1, V_{SUP} down to ~ 2.24 V has results as shown. For the TLIN10285S-Q1, V_{SUP} down to ~ 2.63 V has results as shown. When V_{SUP} drops below these levels the signals are indeterminate.

10.2.2 Detailed Design Procedures

For processors or LIN responder nodes with an internal pull-up on RXD, no external pull-up resistor is needed. For processors or LIN responder nodes without internal pull-up on RXD, an external pull-up resistor is required. Commander node applications require an external 1 k Ω pull-up resistor and serial diode.

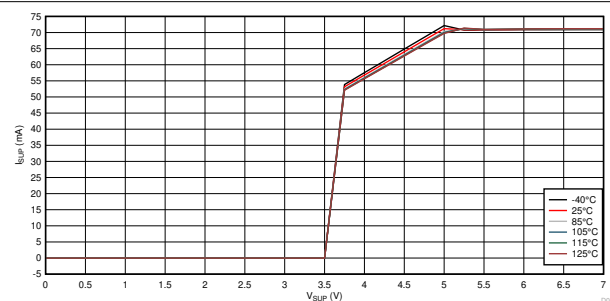
10.2.3 Application Curves

Characteristic curves below show the LDO performance ramping between 0 V and up to 7 V.



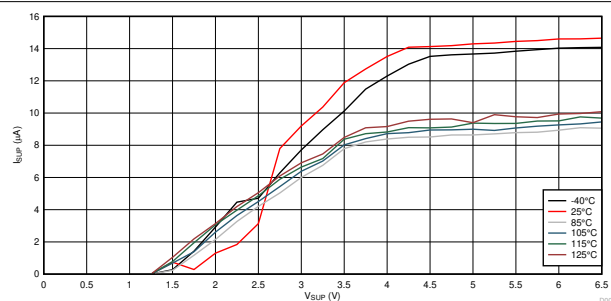
Package = D $V_{CC} = 3.3\text{ V}$ Temperature = Ambient
 $I_{CC} = 70\text{ mA}$

Figure 10-2. I_{SUP} vs V_{SUP} vs Temperature



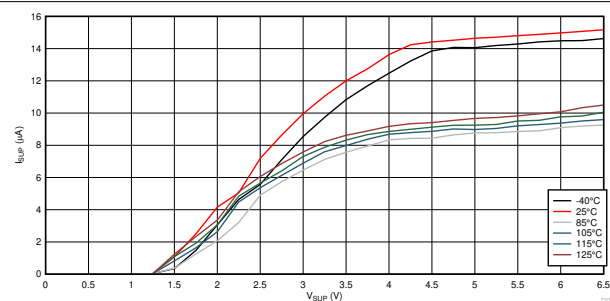
Package = D $V_{CC} = 5\text{ V}$ Temperature = Ambient
 $I_{CC} = 70\text{ mA}$

Figure 10-3. I_{SUP} vs V_{SUP} vs Temperature



Package = D $3.3\text{ V } V_{CC} = \text{Off}$ Temperature = Ambient
Mode = Sleep

Figure 10-4. I_{SUP} vs V_{SUP} vs Temperature Ramp-down



Package = D $5\text{ V } V_{CC} = \text{Off}$ Temperature = Ambient
Mode = Sleep

Figure 10-5. I_{SUP} vs V_{SUP} vs Temperature Ramp-down

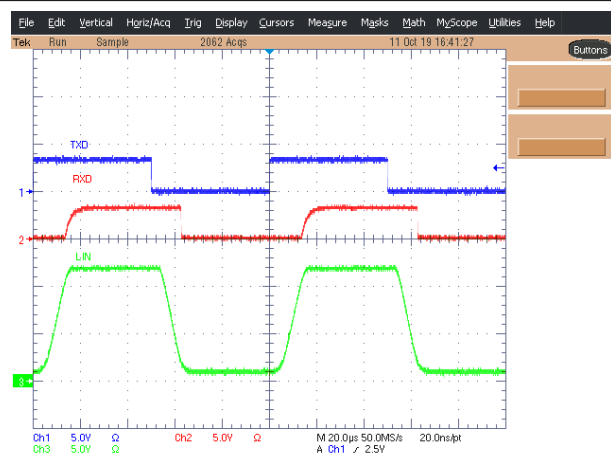


Figure 10-6. LIN Bus Performance

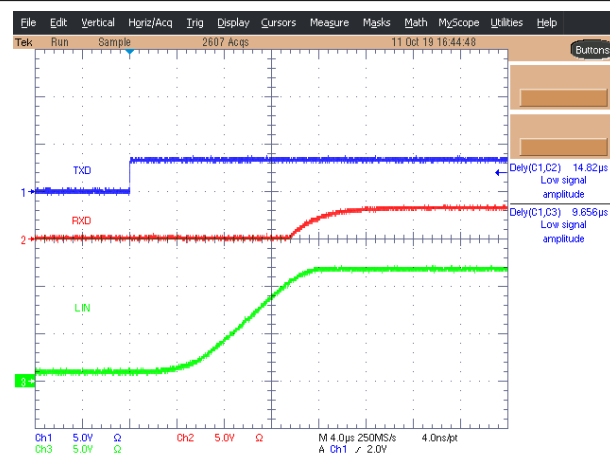
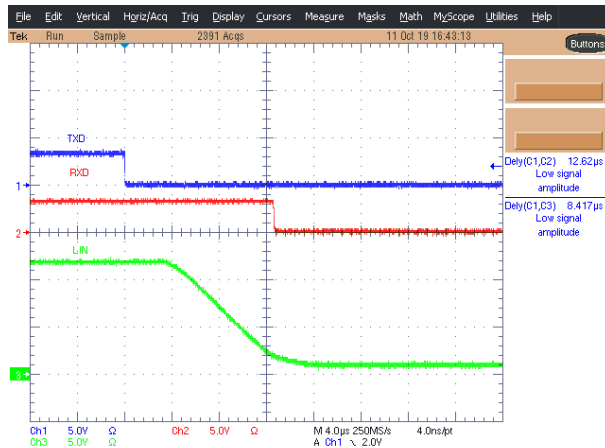
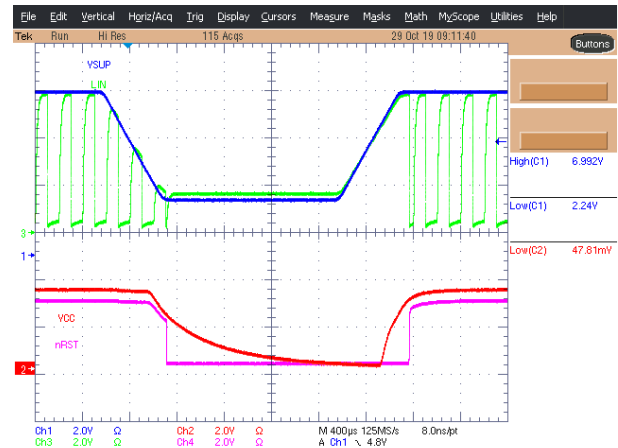


Figure 10-7. Dominant to Recessive Propagation Delay



10-8. Recessive to Dominant Propagation Delay



10-9. TLIN1028S-Q1 Brownout



10-10. TLIN1028S-Q1 Brownout

11 Power Supply Recommendations

The TLIN1028S-Q1 was designed to operate directly off a car battery, or any other DC supply ranging from 5.5 V to 28 V . A 100 nF decoupling capacitor should be placed as close to the V_{SUP} pin of the device as possible.

12 Layout

PCB design should start with understanding that frequency bandwidth from approximately 3 MHz to 3 GHz is needed thus high frequency layout techniques must be applied during PCB design. Placement at the connector also prevents these noisy events from propagating further into the PCB and system.

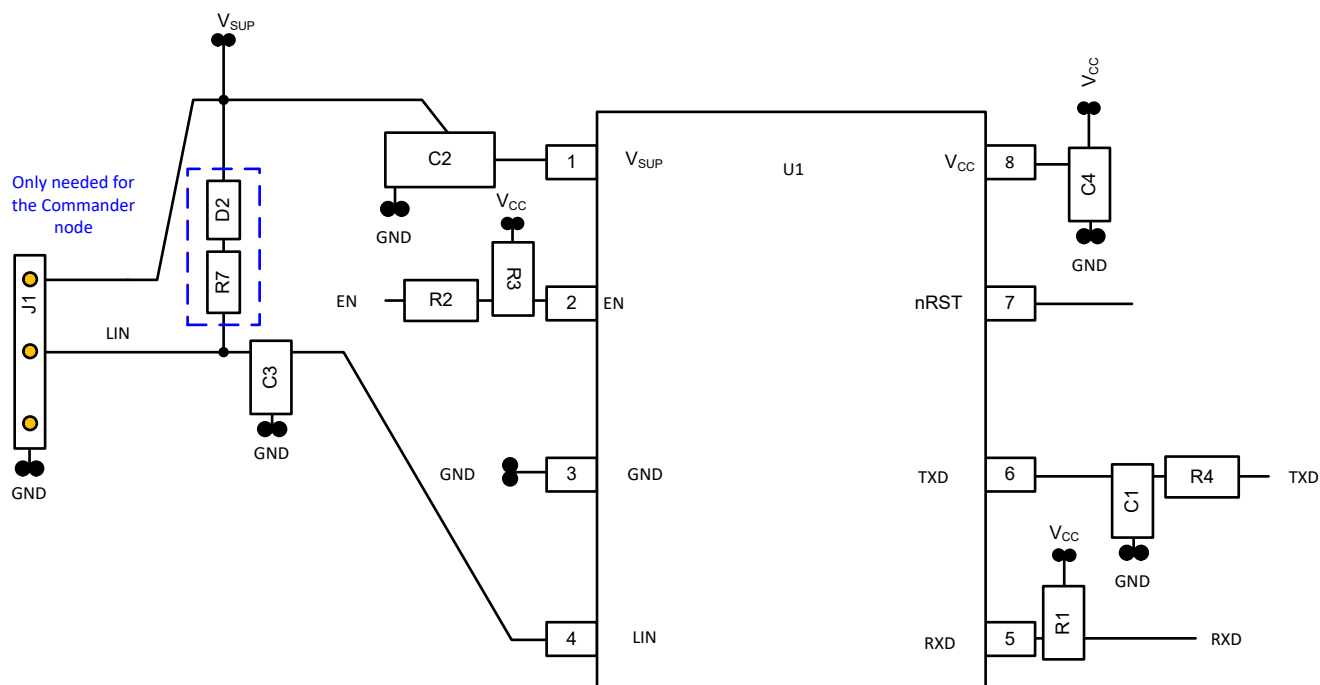
12.1 Layout Guidelines

- **Pin 1 (V_{SUP}):** This is the supply pin for the device. A 100 nF decoupling capacitor should be placed as close to the device as possible.
- **Pin 2 (EN):** EN is an input pin that is used to place the device in a low power sleep mode. If this feature is not used, the pin should be pulled high to the regulated voltage supply of the microprocessor through a series resistor, values between 1 k Ω and 10 k Ω . Additionally, a series resistor may be placed on the pin to limit current on the digital lines in the event of an over-voltage fault.
- **Pin 3 (GND):** This is the ground connection for the device. This pin should be tied to the ground plane through a short trace with the use of two vias to limit total return inductance.
- **Pin 4 (LIN):** This pin connects to the LIN bus. For responder node applications, a 220 pF capacitor to ground is implemented. For commander node applications, an additional series resistor and blocking diode should be placed between the LIN pin and the V_{SUP} pin. See [Figure 10-1](#)
- **Pin 5 (RXD):** The pin is an open-drain output and requires an external pull-up resistor in the range of 1 k Ω to 10 k Ω to function properly. If the microprocessor paired with the transceiver does not have an integrated pull-up, an external pull-up resistor should be placed on RXD. If RXD is connected to the V_{CC} pin a higher pull-up resistor value can be used to reduce standby current.
- **Pin 6 (TXD):** The TXD pin is the transmit input signal to the device from the processors. A series resistor can be placed to limit the input current to the device in the event of an over voltage on this pin. A capacitor to ground can be placed close to the input pin of the device to filter noise.
- **Pin 7 (nRST):** This pin connects to the processors as a reset out.
- **Pin 8 (V_{CC}):** Output source, either 3.3 V or 5 V depending upon the version of the device.

注

All ground and power connections should be made as short as possible and use at least two vias to minimize the total loop inductance.

12.2 Layout Example



12-1. Layout Example

13 Device and Documentation Support

13.1 Documentation Support

13.1.1 Related Documentation

TLIN1028S-Q1 Duty Cycle Over V_{SUP}

For related documentation see the following:

- LIN Standards:
 - ISO/DIS 17987-1: Road vehicles -- Local Interconnect Network (LIN) -- Part 1: General information and use case definition
 - ISO/DIS 17987-4: Road vehicles -- Local Interconnect Network (LIN) -- Part 4: Electrical Physical Layer (EPL) specification 12V/24V
 - SAE J2602-1: LIN Network for Vehicle Applications
 - LIN2.0, LIN2.1, LIN2.2 and LIN2.2A specification
- EMC requirements:
 - SAE J2962-2: TBD
 - HW Requirements for CAN, LIN, FR V1.3: German OEM requirements for LIN
 - ISO 10605: Road vehicles - Test methods for electrical disturbances from electrostatic discharge
 - ISO 11452-4:2011: Road vehicles - Component test methods for electrical disturbances from narrowband radiated electromagnetic energy - Part 4: Harness excitation methods
 - ISO 7637-1:2015: Road vehicles - Electrical disturbances from conduction and coupling - Part 1: Definitions and general considerations
 - ISO 7637-3: Road vehicles - Electrical disturbances from conduction and coupling - Part 3: Electrical transient transmission by capacitive and inductive coupling via lines other than supply lines
 - IEC 62132-4:2006: Integrated circuits - Measurement of electromagnetic immunity 150 kHz to 1 GHz - Part 4: Direct RF power injection method
 - IEC 61967-4
 - CISPR25
- Conformance Test requirements:
 - ISO/DIS 17987-7: Road vehicles -- Local Interconnect Network (LIN) -- Part 7: Electrical Physical Layer (EPL) conformance test specification
 - SAE J2602-2: LIN Network for Vehicle Applications Conformance Test

TLINx441 LDO Performance, SLLA427

13.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

13.3 サポート・リソース

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13.4 Trademarks

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13.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

13.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
TLIN10283SDRQ1	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TL083
TLIN10283SDRQ1.A	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TL083
TLIN10285SDRQ1	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TL085
TLIN10285SDRQ1.A	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TL085

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "-" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLIN10283SDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLIN10285SDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLIN10283SDRQ1	SOIC	D	8	2500	353.0	353.0	32.0
TLIN10285SDRQ1	SOIC	D	8	2500	353.0	353.0	32.0



PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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